

# EE 330

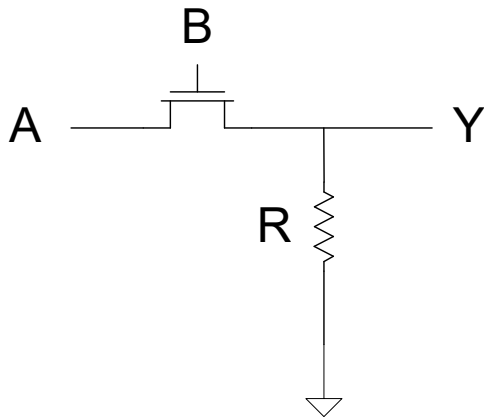
## Lecture 17

MOSFET Modeling

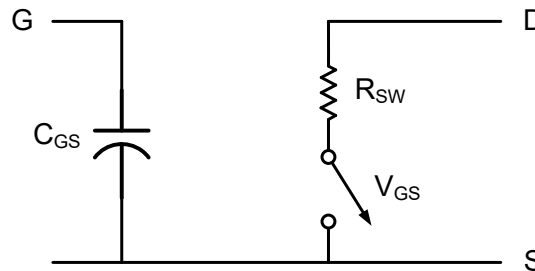
# Fall 2024 Exam Schedule

Exam 1	Friday	Sept 27
Exam 2	Friday	October 25
Exam 3	Friday	Nov 22
Final Exam	Monday	Dec 16 12:00 - 2:00
PM		

# Limitations of Existing MOSFET Models



What is Y when  $A=B=V_{DD}$

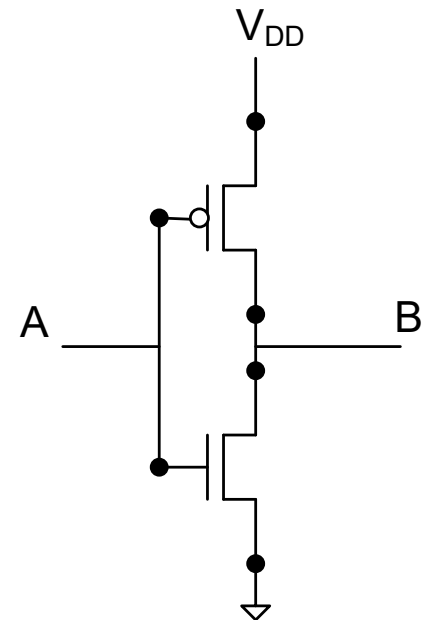


*For minimum-sized devices in a 0.5u process with  $V_{DD}=5V$*

$$C_{GS} \cong 1.5fF$$

$$R_{sw} \cong \left. \begin{array}{l} 2K\Omega \text{ n-channel} \\ 6K\Omega \text{ p-channel} \end{array} \right\}$$

What is  $R_{sw}$  if MOSFET is not minimum sized?

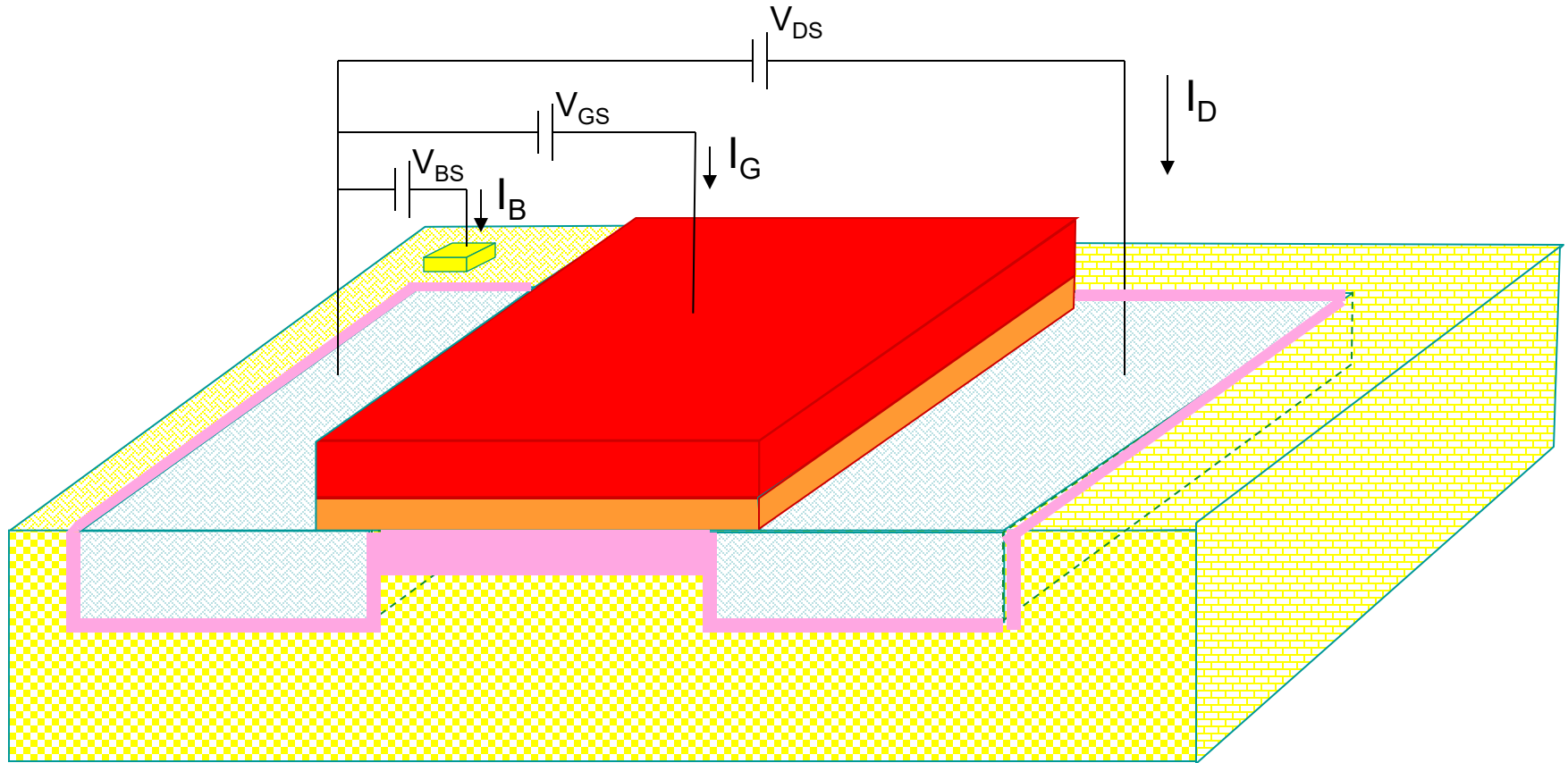


What is power dissipation if A is stuck at an intermediate voltage?

**Better Model of MOSFET is Needed!**

Review from last lecture

# n-Channel MOSFET Operation and Model

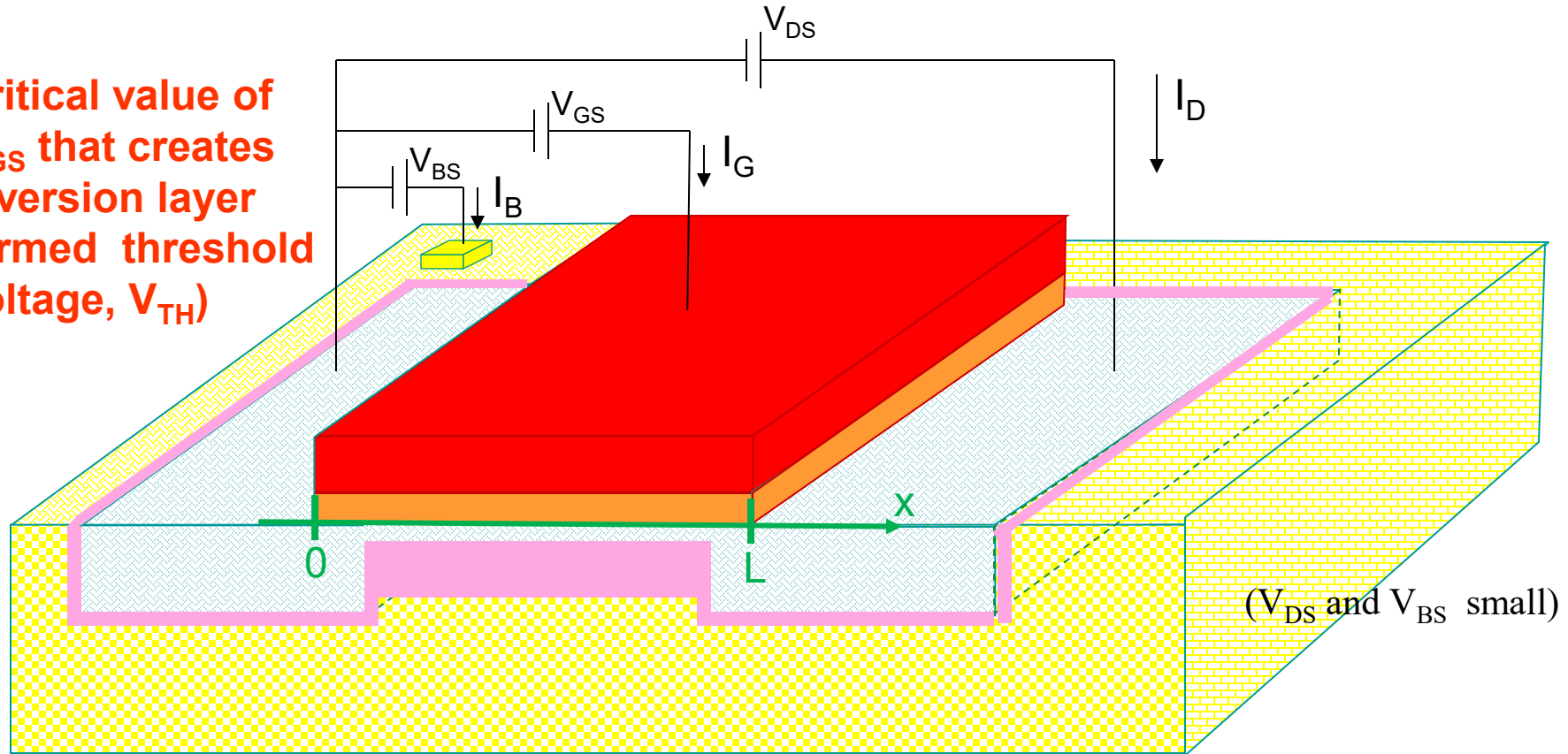


$$\begin{aligned} I_D &= 0 \\ I_G &= 0 \\ I_B &= 0 \end{aligned}$$

Model in Cutoff Region

# n-Channel MOSFET Operation and Model

Critical value of  $V_{GS}$  that creates inversion layer termed threshold voltage,  $V_{TH}$ )



Increase  $V_{GS}$  more

Inversion layer forms in channel

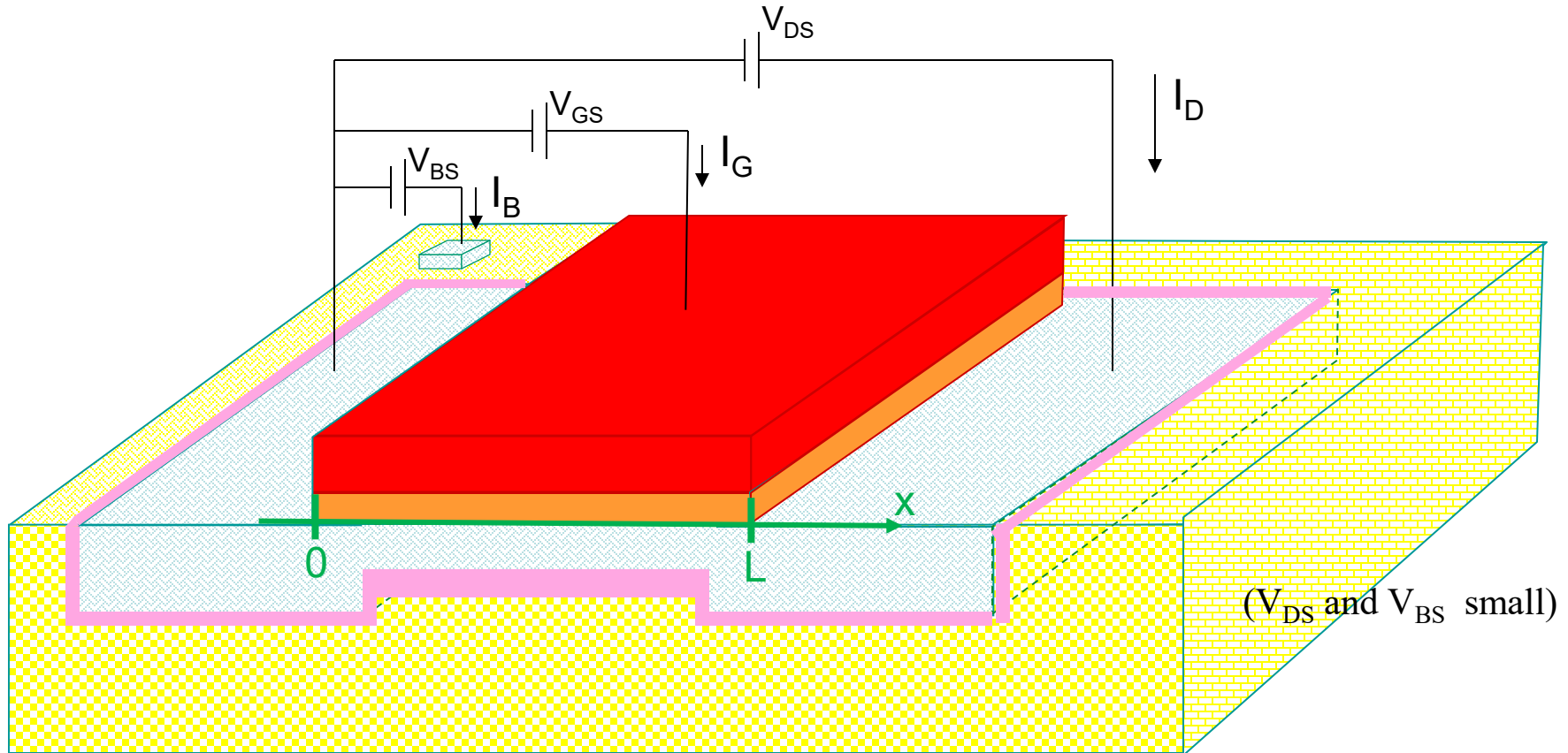
Inversion layer will support current flow from D to S

Channel behaves as thin-film resistor

$$\begin{aligned} I_D R_{CH} &= V_{DS} \\ I_G &= 0 \\ I_B &= 0 \end{aligned}$$

Review from last lecture

# n-Channel MOSFET Operation and Model



Increase  $V_{GS}$  more (with  $V_{DS}$  and  $V_{BS}$  still small)

$V_{GC}(x)$  approx. constant for small  $V_{DS}$

Inversion layer in channel thickens

$R_{CH}$  will decrease

Termed “ohmic” or “triode” region of operation

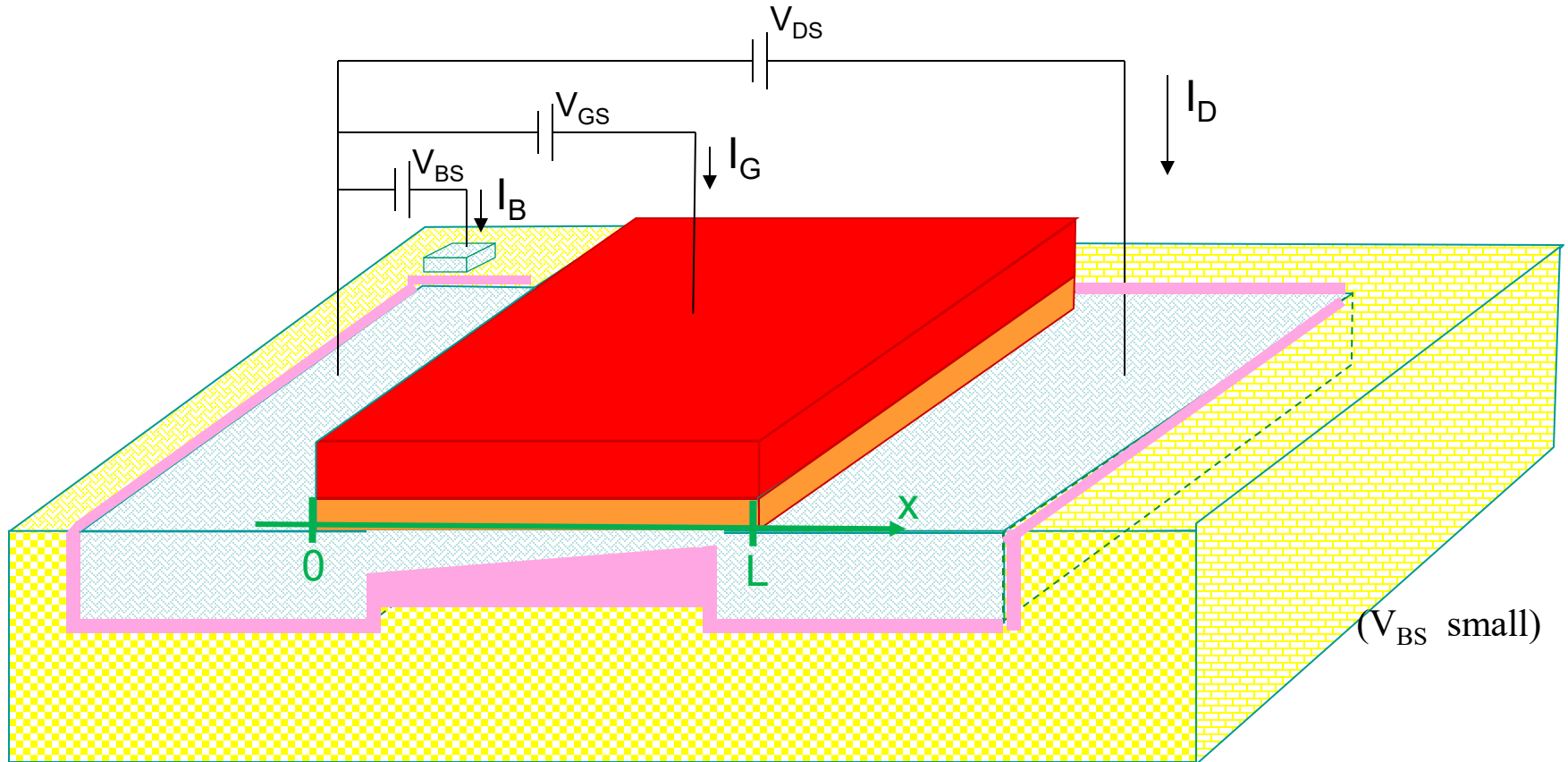
$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

Review from last lecture

# n-Channel MOSFET Operation and Model



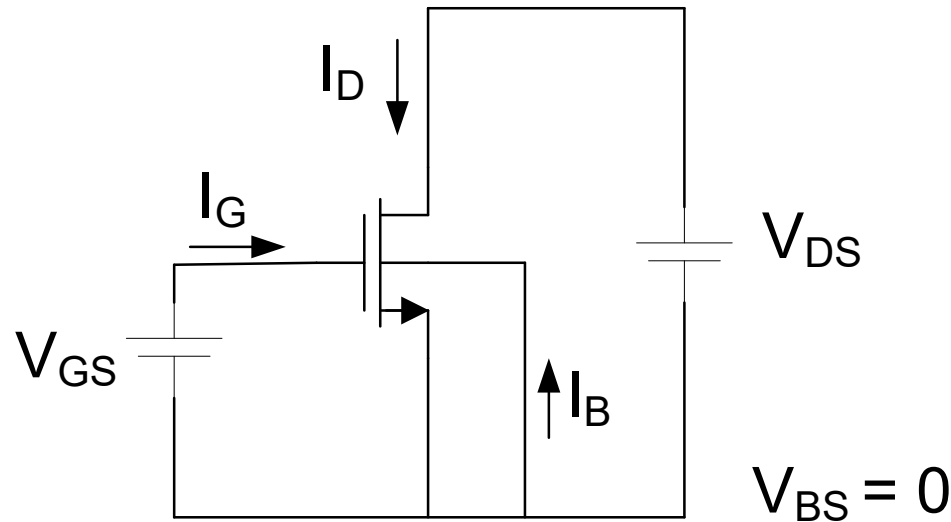
Increase  $V_{DS}$

$V_{GC}(x)$  changes with  $x$  for larger  $V_{DS}$

Inversion layer thins near drain  
 $I_D$  no longer linearly dependent upon  $V_{DS}$   
Still termed “ohmic” or “triode” region of operation

$$\begin{aligned} I_D &=? \\ I_G &=0 \\ I_B &=0 \end{aligned}$$

# Triode Region of Operation



For  $V_{DS}$  larger

~~$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$$~~

$$I_D = \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$

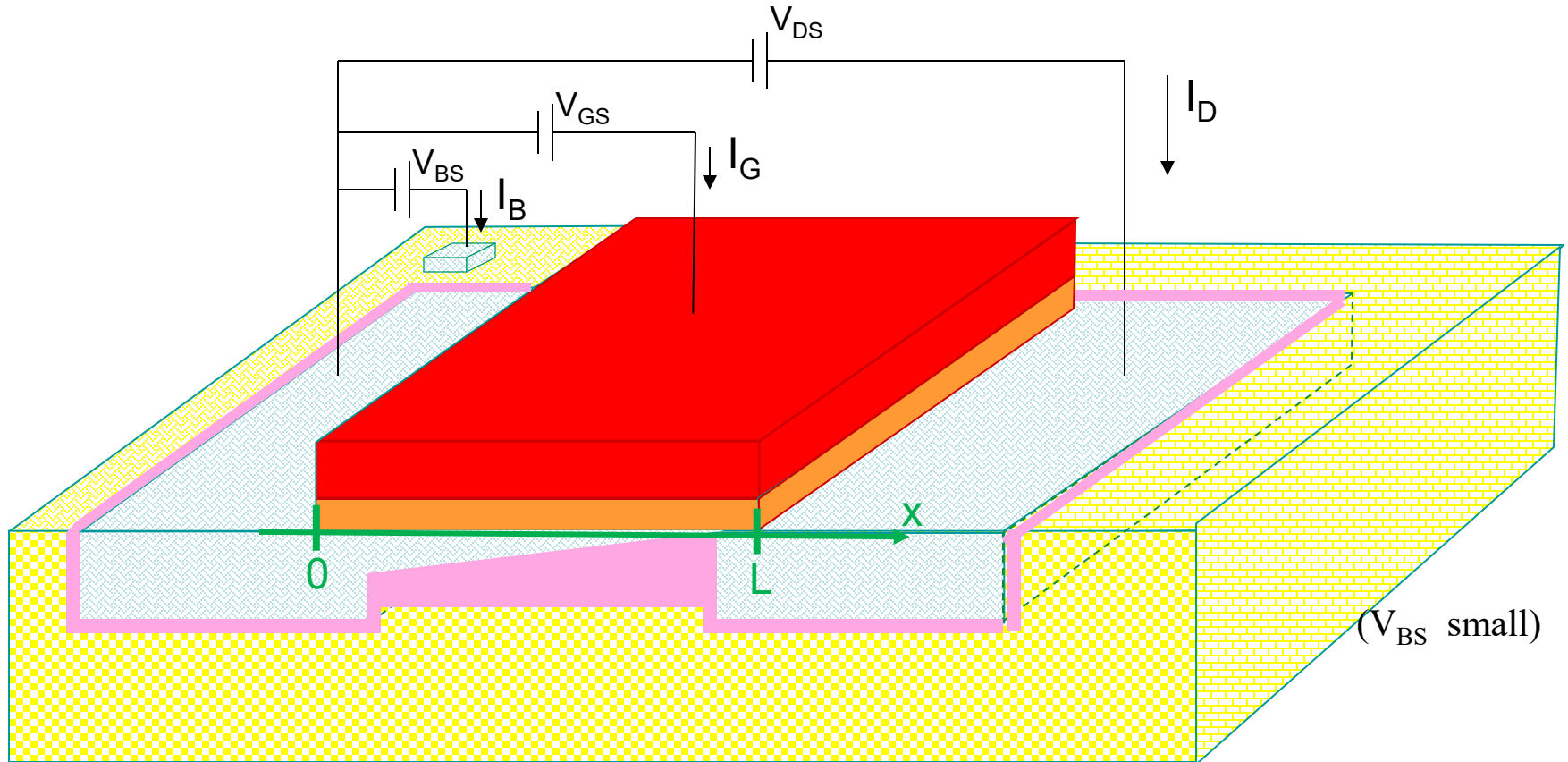
$$I_G = I_B = 0$$

Model in Triode Region



Review from last lecture

# n-Channel MOSFET Operation and Model



Increase  $V_{DS}$  even more

$V_{GC}(L) = V_{TH}$  when channel saturates

Inversion layer disappears near drain

Termed "saturation" region of operation

Saturation first occurs when  $V_{DS} = V_{GS} - V_{TH}$

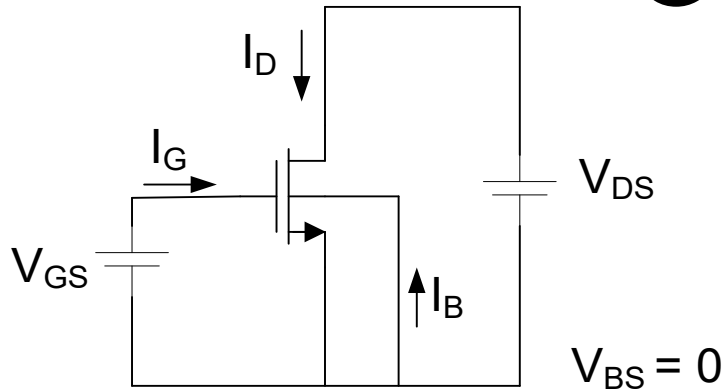
$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

# Saturation Region of Operation

Review from last lecture



$$I_D = \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$

*or equivalently*

$$I_D = \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{GS} - V_{TH}}{2} \right) (V_{GS} - V_{TH})$$

*or equivalently*

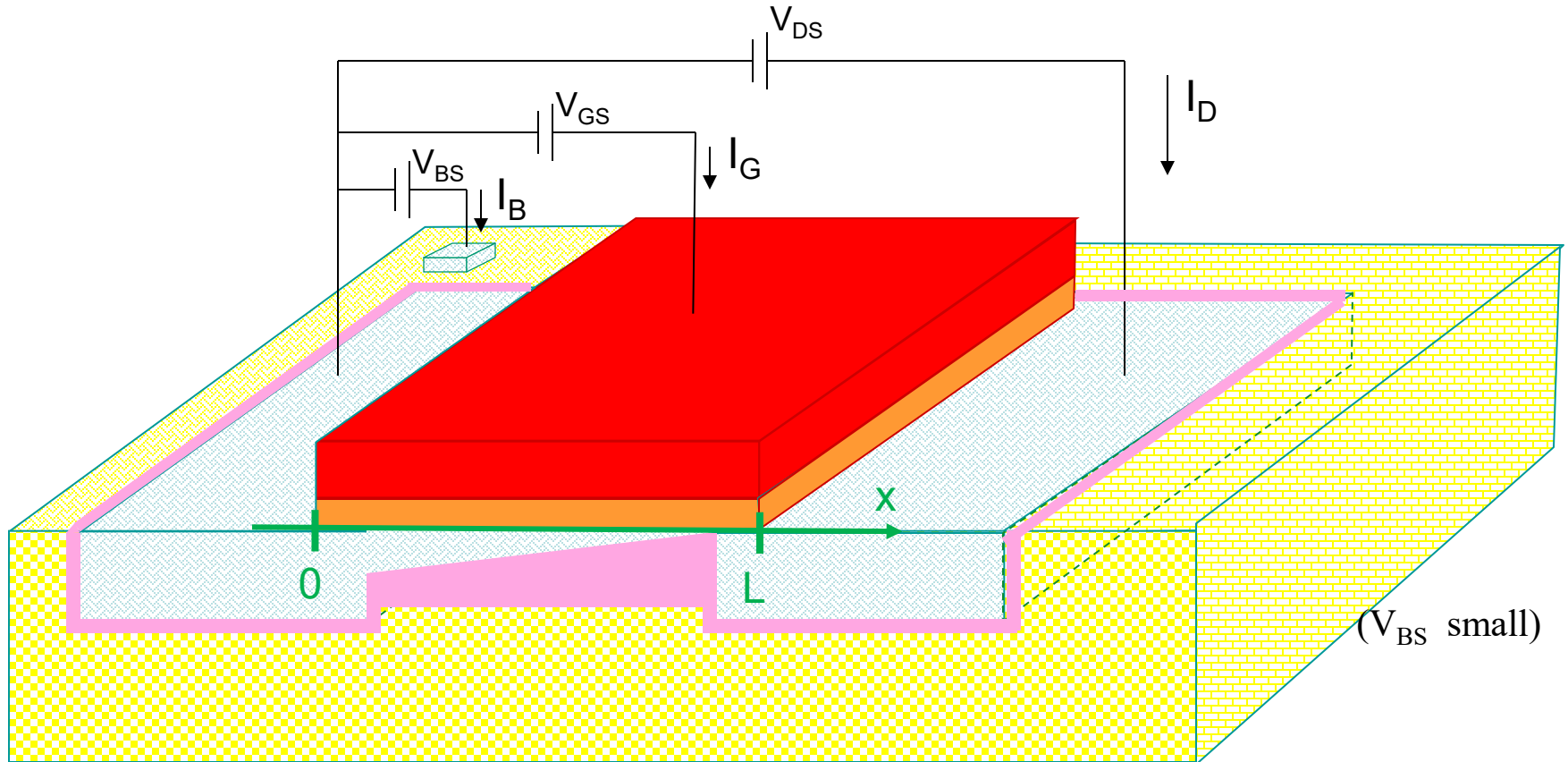
$$I_D = \frac{\mu C_{OX} W}{2L} (V_{GS} - V_{TH})^2$$

$$I_G = I_B = 0$$

For  $V_{DS}$  at onset of saturation

Review from last lecture

# n-Channel MOSFET Operation and Model



Increase  $V_{DS}$  even more (beyond  $V_{GS} - V_{TH}$ )

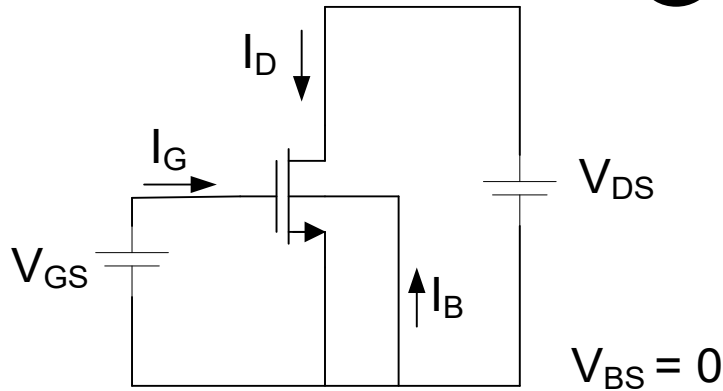
Nothing much changes !!

Termed “saturation” region of operation

$$\begin{aligned} I_D &=? \\ I_G &=0 \\ I_B &=0 \end{aligned}$$

# Saturation Region of Operation

Review from last lecture



For  $V_{DS}$  in Saturation

$$I_D = \frac{\mu C_{OX} W}{2L} (V_{GS} - V_{TH})^2$$

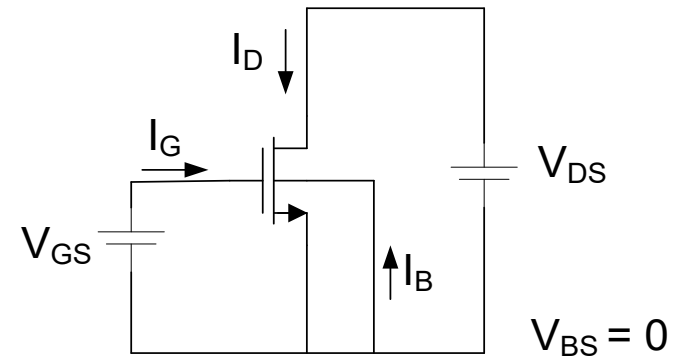
$$I_G = I_B = 0$$

Model in Saturation Region

# Model Summary

n-channel MOSFET

Notation change:  $V_T = V_{TH}$ , don't confuse  $V_T$  with  $V_t = kT/q$



$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} & \text{Cutoff} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} & \text{Triode} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} & \text{Saturation} \end{cases}$$

$$I_G = I_B = 0$$

Model Parameters:  $\{\mu, V_{TH}, C_{OX}\}$  Design Parameters:  $\{W,$

$L\}$  This is a piecewise model (not piecewise linear though)

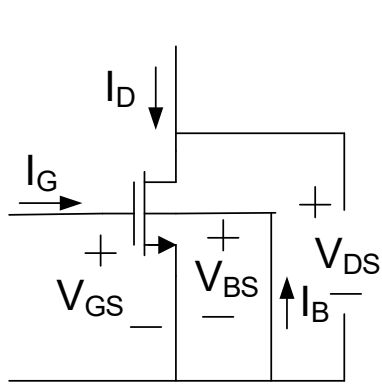
Piecewise model is continuous at transition between regions

(Deep triode special case of triode where  $V_{DS}$  is small  $R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$ )

**Note: This is the third model we have introduced for the MOSFET**

# Model Summary

n-channel MOSFET



$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

$V_{BS} = 0$

$$I_G = I_B = 0$$

Observations about this model (developed for  $V_{BS}=0$ ):

$$I_D = f_1(V_{GS}, V_{DS})$$

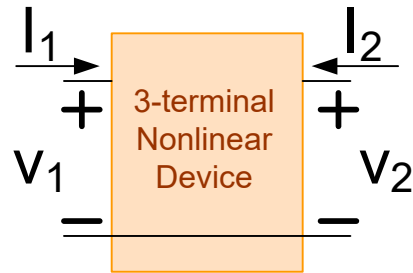
$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

This is a nonlinear model characterized by the functions  $f_1$ ,  $f_2$ , and  $f_3$  where we have assumed that the port voltages  $V_{GS}$  and  $V_{DS}$  are the independent variables and the drain currents are the dependent variables

Review from last lecture

# General Nonlinear Models

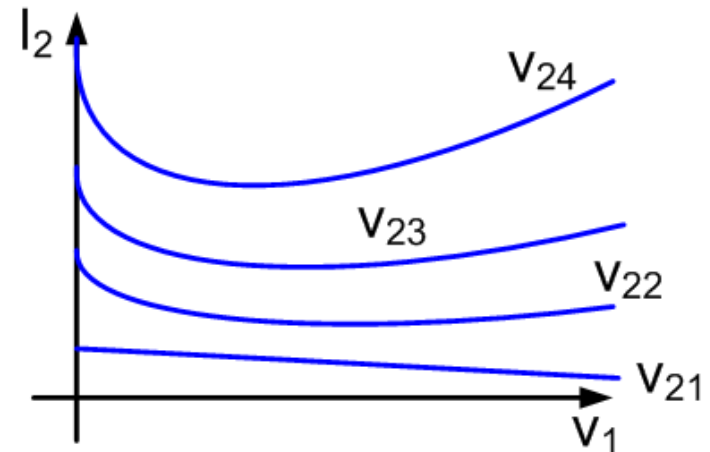
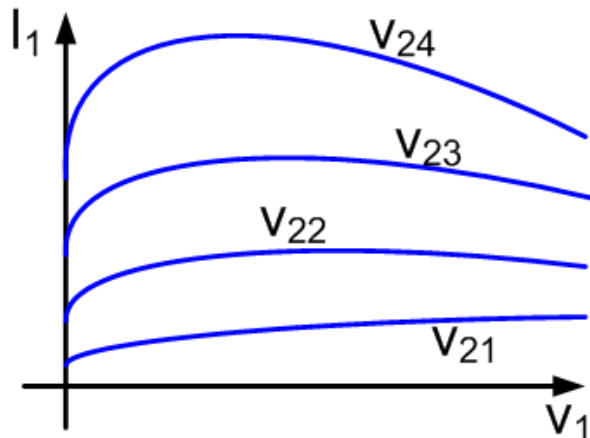


$$I_1 = f_1(V_1, V_2)$$

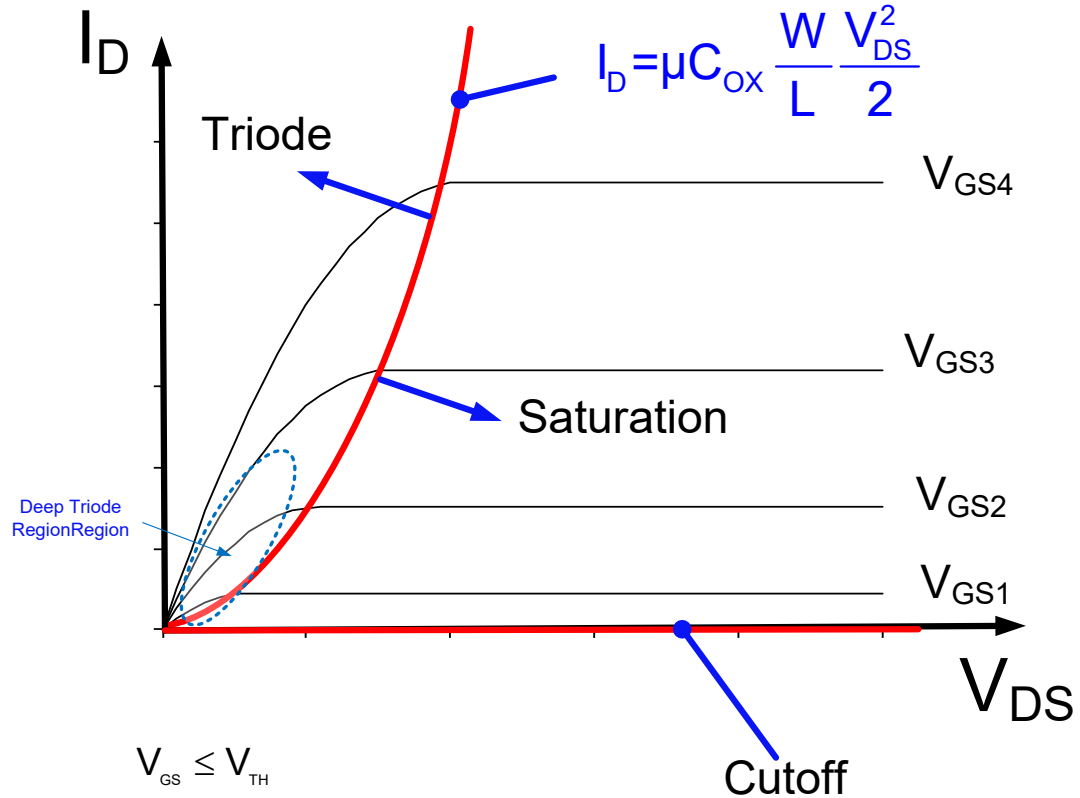
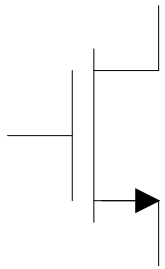
$$I_2 = f_2(V_1, V_2)$$

$I_1$  and  $I_2$  are 3-dimensional relationships which are often difficult to visualize

Two-dimensional representation of 3-dimensional relationships



# Graphical Representation of MOS Model



$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{ox} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_{TH})^2 & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

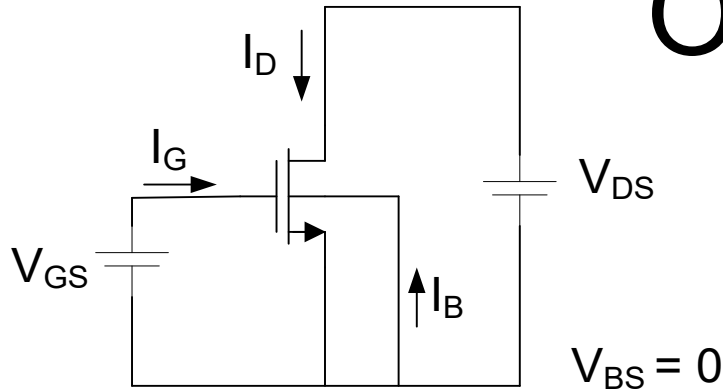
$$I_G = I_B = 0$$

Parabola separated triode and saturation regions and corresponds to  $V_{DS} = V_{GS} - V_{TH}$



Review from last lecture

# Saturation Region of Operation



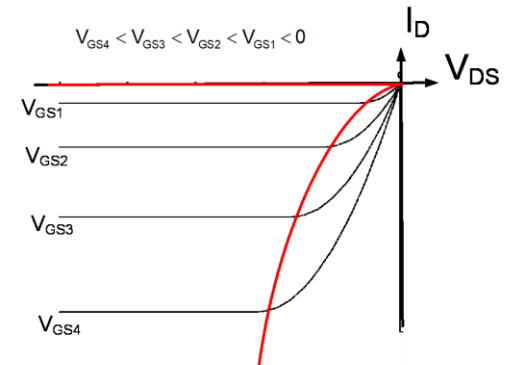
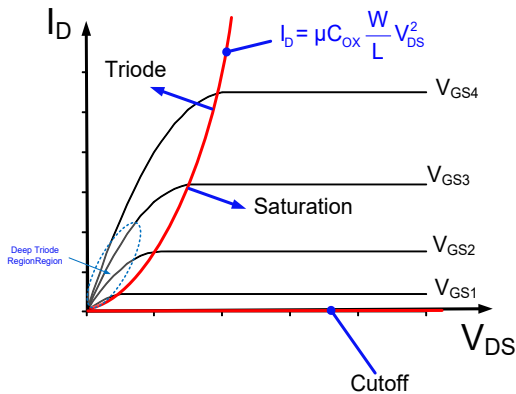
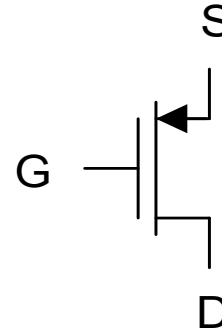
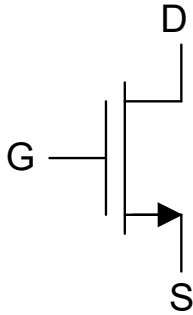
For  $V_{DS}$  in Saturation

$$I_D = \frac{\mu C_{OX} W}{2L} (V_{GS} - V_{TH})^2$$

$$I_G = I_B = 0$$

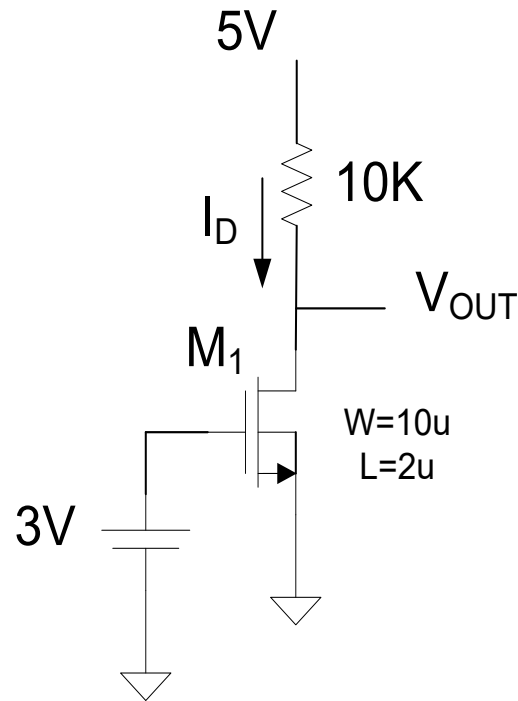
Model in Saturation Region

# PMOS and NMOS Models



- Functional form identical, sign changes and parameter values different
- Will give details about p-channel model later

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_{TH}=1V$  and  $\mu C_{OX}=100\mu AV^{-2}$

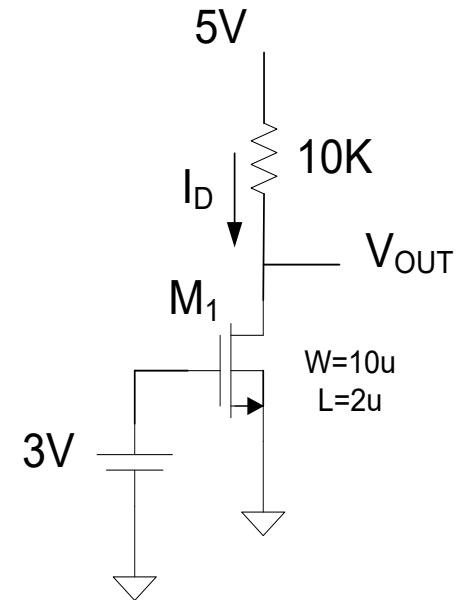


Solution:

Since  $V_{GS} > V_{TH}$ ,  $M_1$  is operating in either saturation or triode region

Strategy will be to guess region of operation, solve, and then verify region

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_{TH}=1V$  and  $\mu C_{OX}=100\mu AV^{-2}$



Solution:

Guess  $M_1$  in saturation

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{2L} (3 - V_{TH})^2$$

Required verification:  $V_{DS} > V_{GS} - V_{TH}$

Can eliminate  $I_D$  between these 2 equations to obtain  $V_{OUT}$

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_{TH}=1V$  and  $\mu C_{OX}=100\mu AV^{-2}$

Guess  $M_1$  in saturation

Required verification:  $V_{DS} > V_{GS} - V_T$

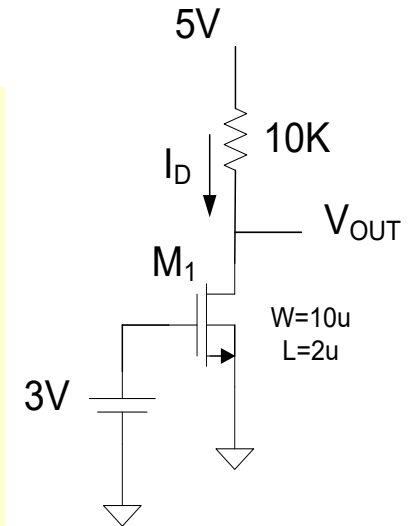
$$\left. \begin{aligned} 5V &= I_D 10K + V_{OUT} \\ I_D &= \frac{\mu C_{OX} W}{2L} (3 - V_{TH})^2 \end{aligned} \right\}$$

$$V_{OUT} = 5V - 10K \left[ \frac{100\mu AV^{-2} 10\mu}{2 \cdot 2\mu} (2V)^2 \right]$$

$$V_{OUT} = -5V$$

Verification:  $V_{DS} = V_{OUT}$

$-5 >? 2V - - 0$  No! So verification fails and Guess of region is invalid



Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume  $V_{TH}=1V$  and  $\mu C_{OX}=100\mu AV^{-2}$

Guess  $M_1$  in triode

Required verification:  $V_{DS} < V_{GS} - V_T$

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{L} \left( 3 - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$

$$V_{OUT} = 5V - 10K \left[ \frac{100\mu AV^{-2} 10\mu}{2\mu} \left( 2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

$$V_{OUT} = 5V - \left[ 5 \left( 2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

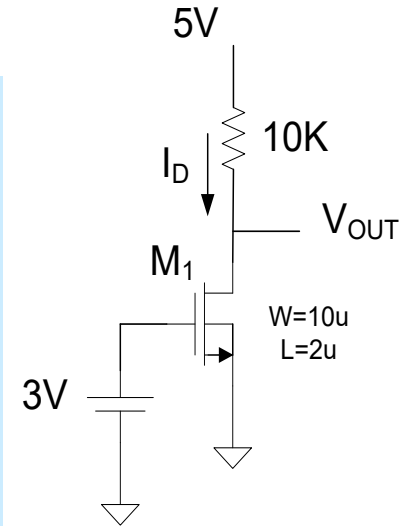
Solving for  $V_{OUT}$ , obtain

$$V_{OUT} = 0.515V$$

Verification:  $V_{DS} = V_{OUT}$

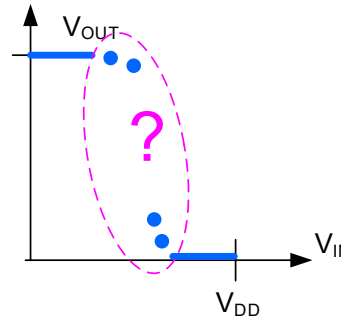
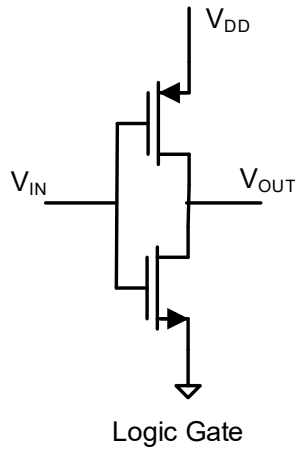
$0.515 < 2V$  Yes!

So verification succeeds and triode region is valid

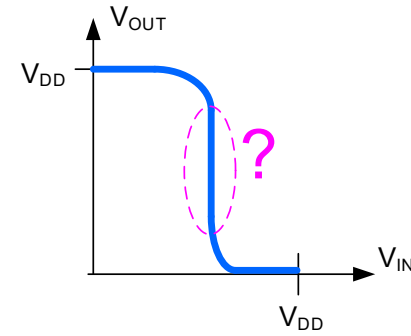


$$V_{OUT} = 0.515V$$

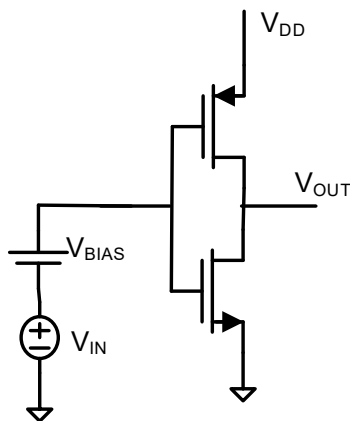
# Limitations of Existing Models



Switch-Level Models



Simple square-law Model



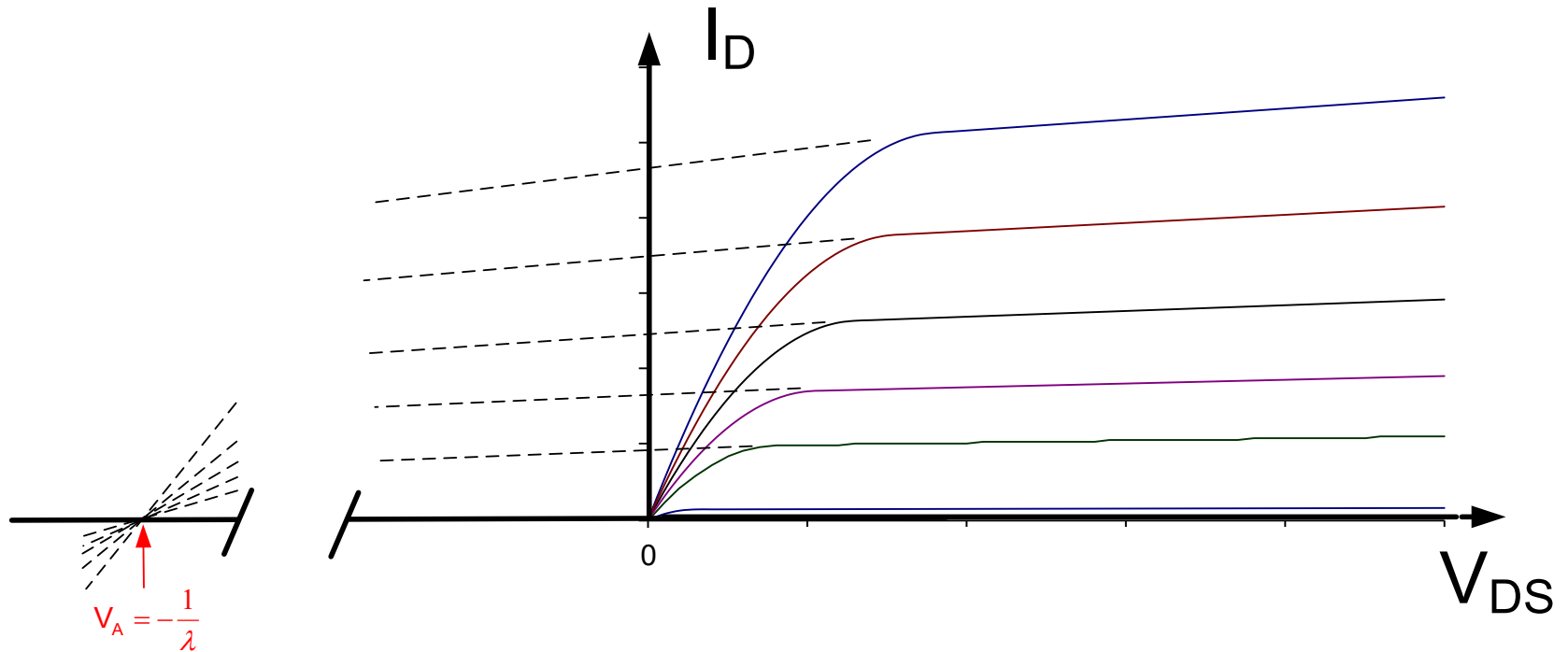
Switch-Level Models

Simple square-law Model



Voltage Gain  
Input/Output Relationship ?

# Model Extensions



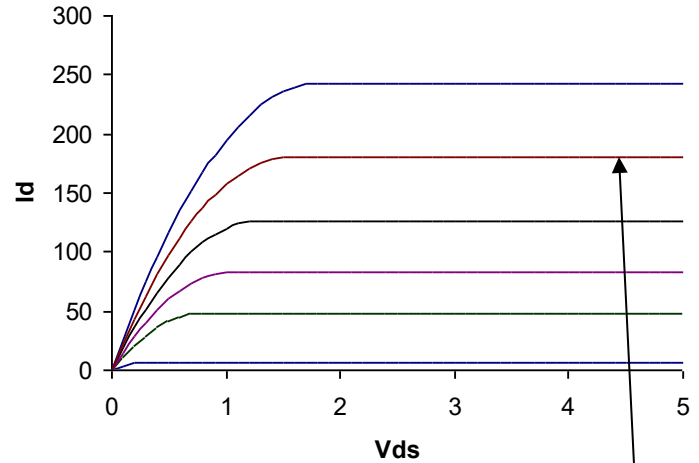
Projections intersect  $-V_{DS}$  axis at same point, termed Early Voltage

Typical values from -20V to -200V

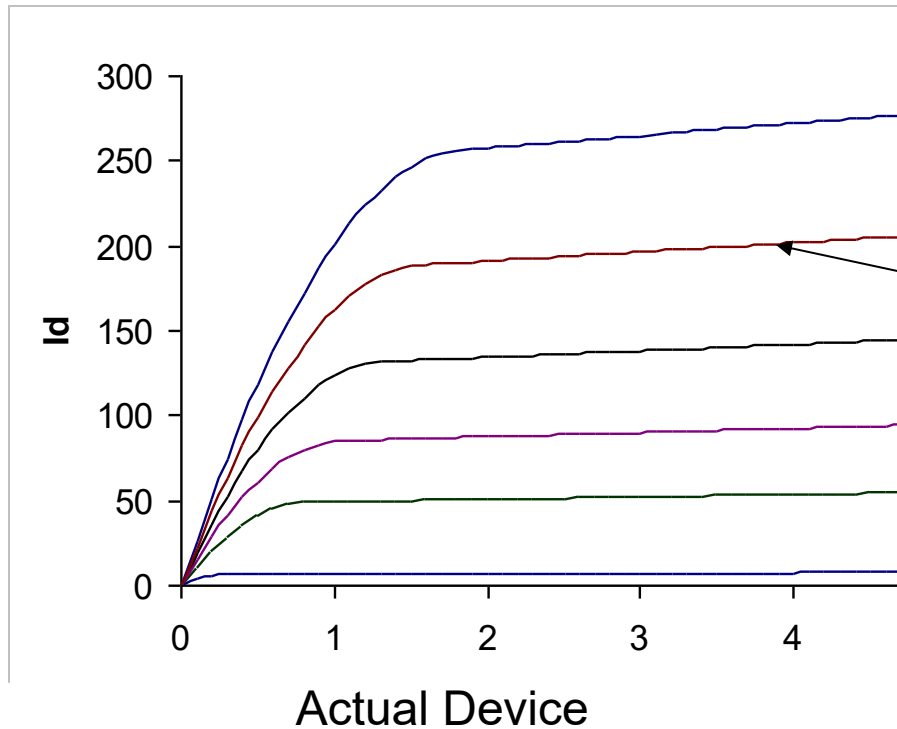
Usually use parameter  $\lambda$  instead of  $V_A$  in MOS model



# Model Extensions



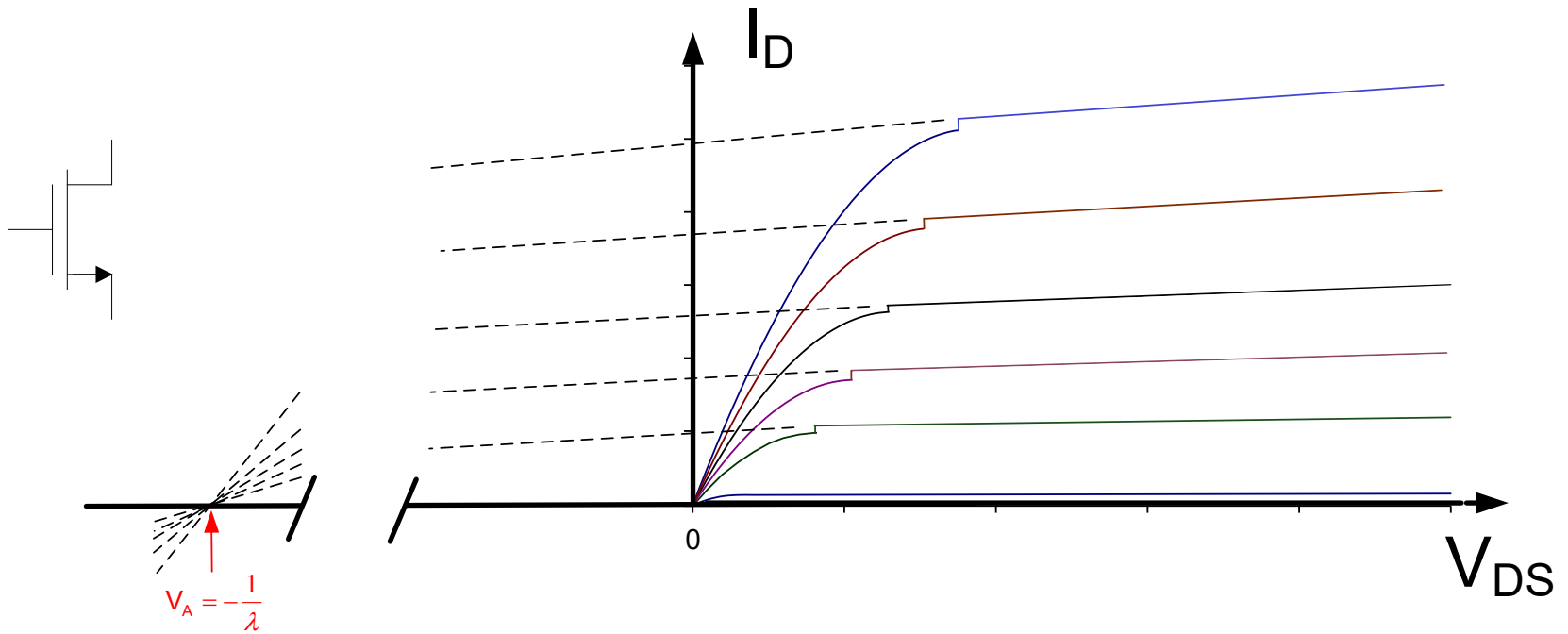
Existing Model



Actual Device

Slope is not 0

# Model Extensions

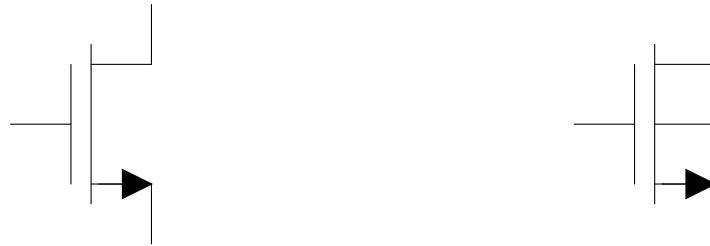


$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

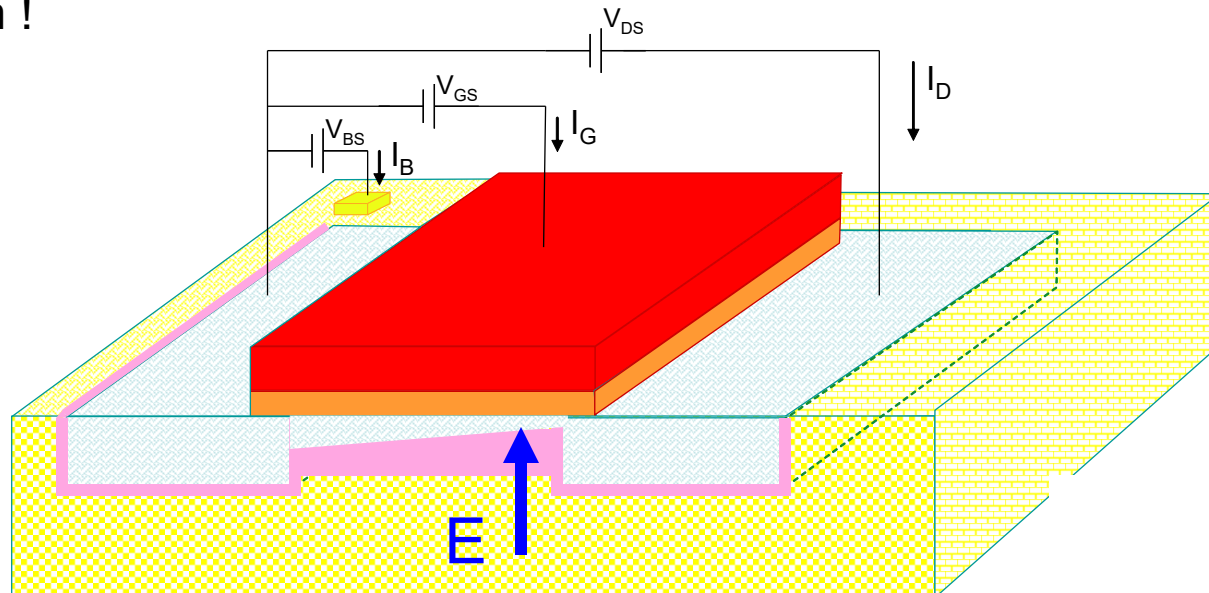
Note: This introduces small discontinuity in model at SAT/Triode transition

# Further Model Extensions

Existing model does not depend upon the bulk voltage !



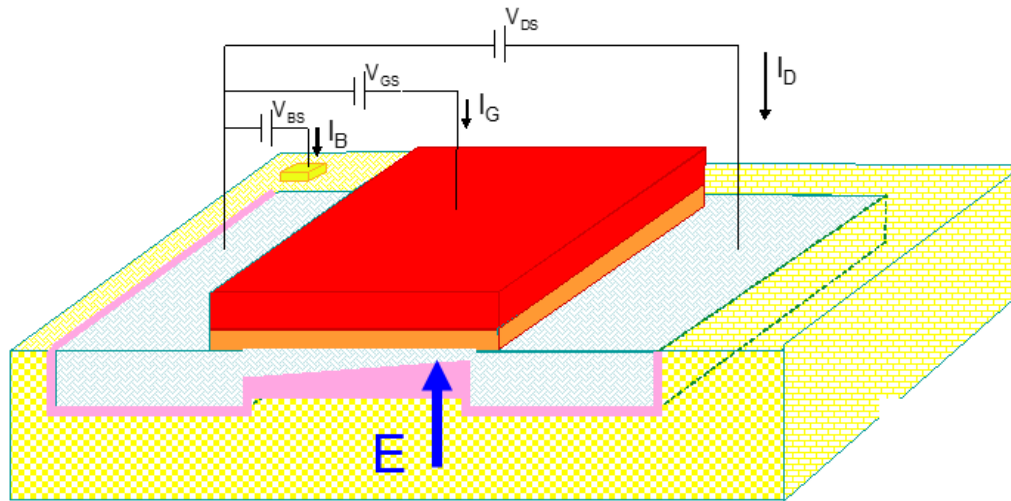
Observe that changing the bulk voltage will change the electric field in the channel region !



# Further Model Extensions

Existing model does not depend upon the bulk voltage !

Observe that changing the bulk voltage will change the electric field in the channel region !



Changing the bulk voltage will change the thickness of the inversion layer

Changing the bulk voltage will change the threshold voltage of the device

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

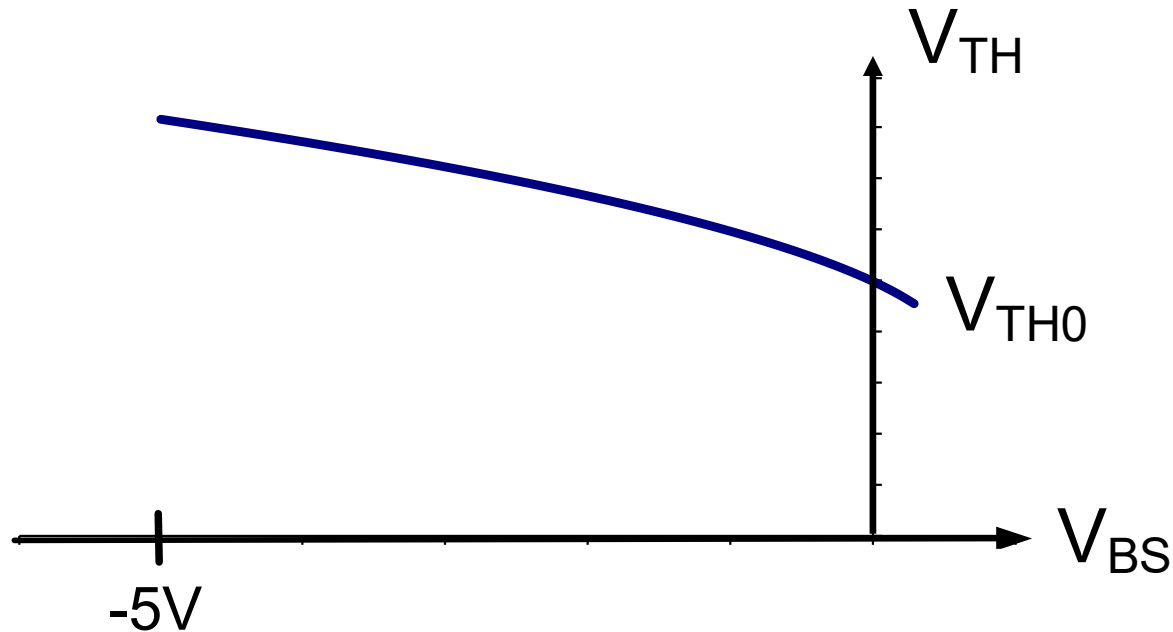
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$\phi$  is the surface potential (some authors use symbol  $\Phi_S$ )  
 $\gamma$  is the bulk threshold

## Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$

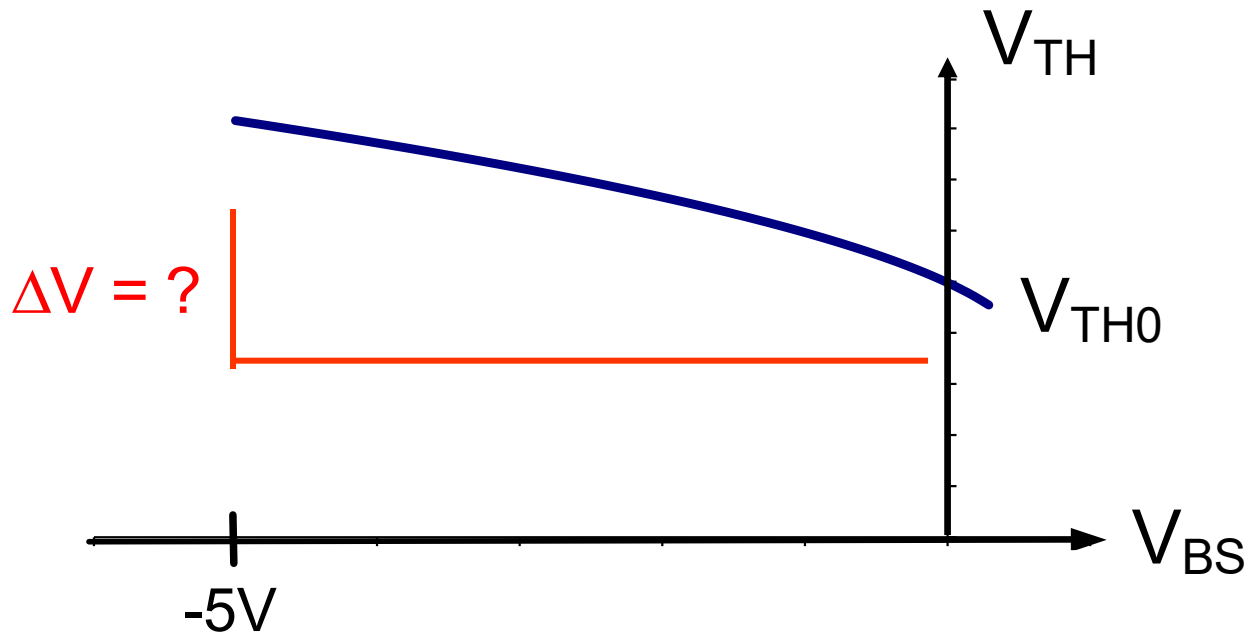


- Bulk-Diffusion Generally Reverse Biased ( $V_{BS} < 0$  or at least  $V_{BS} < 0.3V$ ) for n-channel
- Shift in threshold voltage with bulk voltage can be substantial
- Often  $V_{BS} = 0$

# Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$



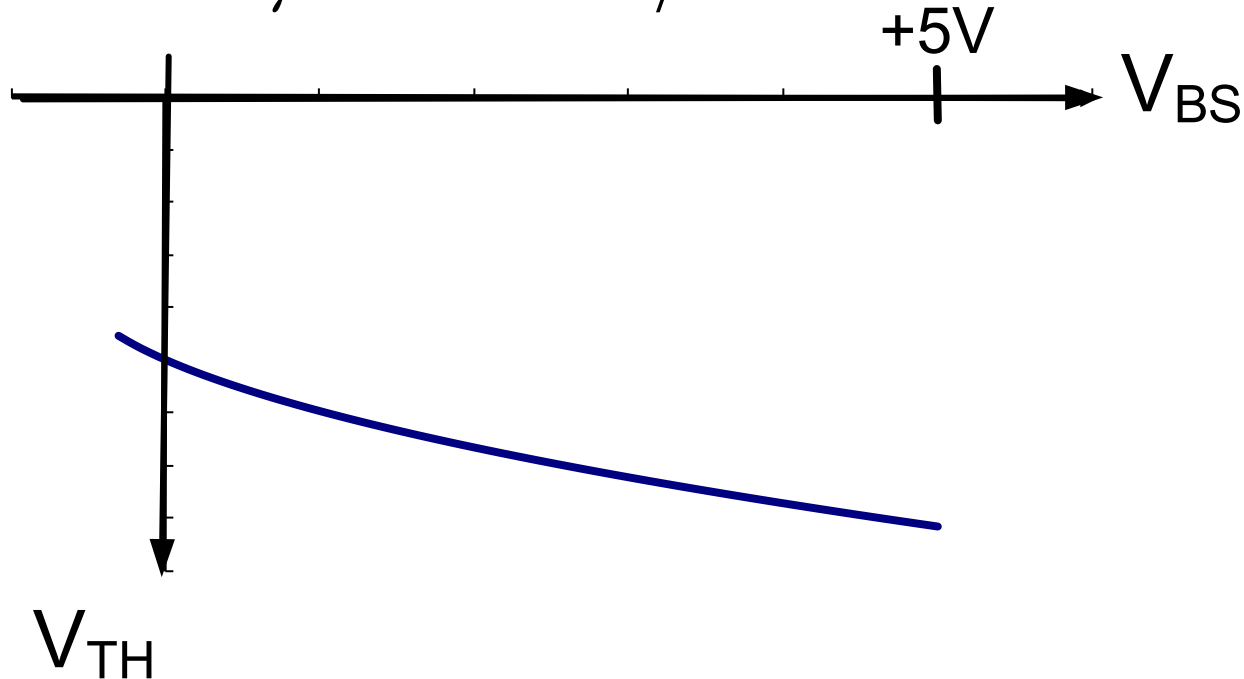
$$\Delta V = V_{TH} - V_{TH0} = \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\Delta V \cong 0.4 \left( \sqrt{0.6V - (-5V)} - \sqrt{0.6} \right) \cong 0.64V$$

## Typical Bulk Effects on Threshold Voltage for p-channel Devices

$$V_{TH} = V_{TH0} - \gamma \left( \sqrt{\phi + V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$

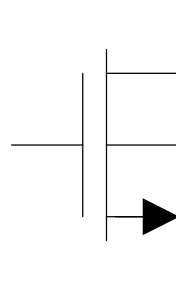


- Bulk-Diffusion Generally Reverse Biased ( $V_{BS} > 0$  or at least  $V_{BS} > -0.3V$ ) for p-channel
- Same functional form as for n-channel but  $V_{TH0} < 0$
- Magnitude of threshold voltage increases with magnitude of reverse bias

# Model Extension Summary

$$I_G = 0$$

$$I_B = 0$$



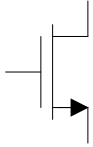
$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

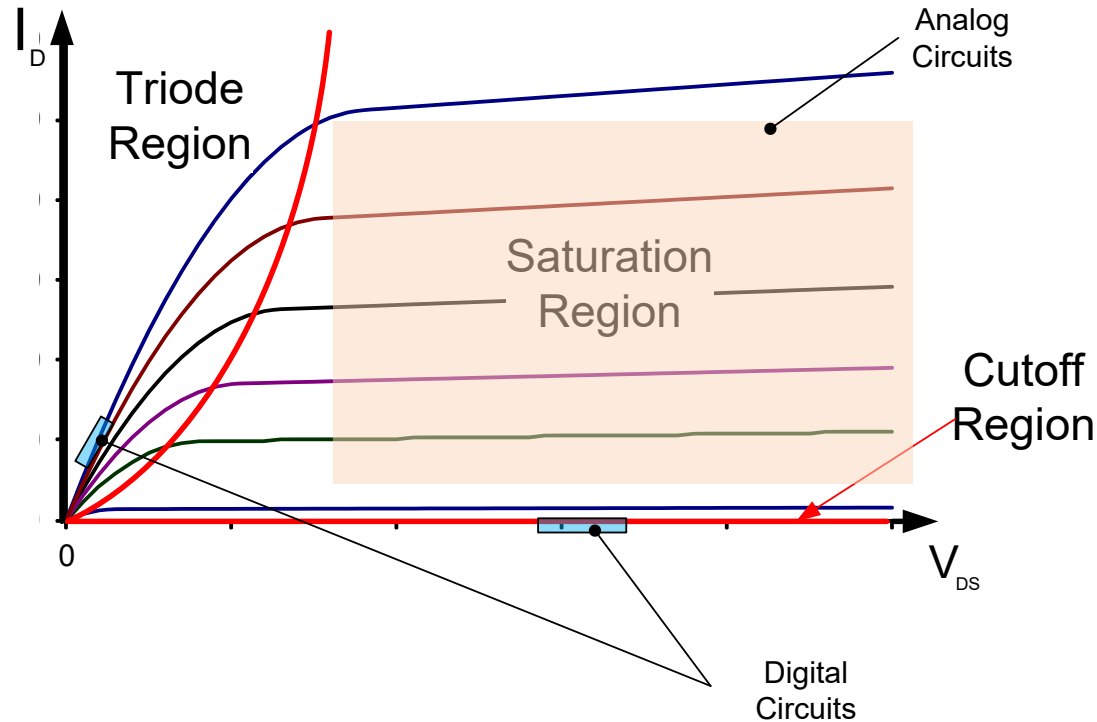
Model Parameters :  $\{\mu, C_{OX}, V_{TH0}, \phi, \gamma, \lambda\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom  $W/L$





# Operation Regions by Applications



Most analog circuits operate in the saturation region

(basic VVR operates in triode and is an exception)

Most digital circuits operate in triode and cutoff regions and switch between these two with Boolean inputs

# Model Extension (short devices)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

As the channel length becomes very short, velocity saturation will occur in the channel and this will occur with electric fields around  $2V/u$ . So, if a gate length is around  $1u$ , then voltages up to  $2V$  can be applied without velocity saturation. But, if gate length decreases and voltages are kept high, velocity saturation will occur

$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \frac{\theta_2}{\theta_1} \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\alpha} & V_{GS} \geq V_{TH} \quad V_{DS} \geq \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

# Model Extension (short devices)

(n-channel device)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \frac{\theta_2}{\theta_1} \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\alpha} & V_{GS} \geq V_{TH} \quad V_{DS} \geq \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

No longer a square-law model (some term it an  $\alpha$ -power or  $\alpha$ -law model)

For long devices,  $\alpha=2$

Channel length modulation ( $\lambda$ ) and bulk effects can be added to the velocity Saturation as well

Degrading of  $\alpha$  is not an attractive limitation of the MOSFET

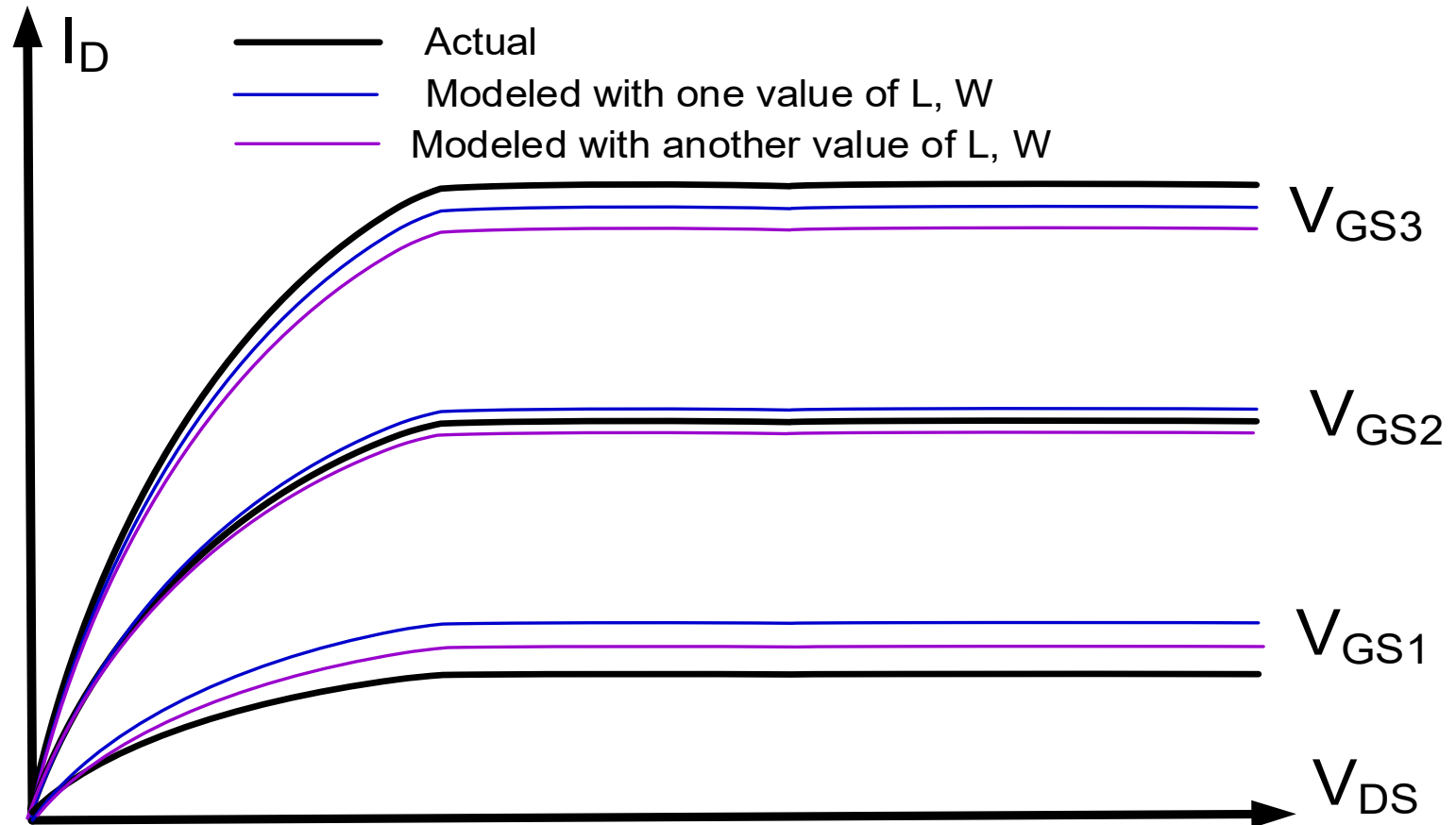
Be aware of existence but of little use !

(too complicated for analytical calculations, not accurate enough for simulations)

# Model Extension (BSIM model)

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          LEVEL = 49
+XJ = 1.5E-7          NCH = 1.7E17        TOX = 1.42E-8
+K1 = 0.8976376      K2 = -0.09255        VTH0 = 0.629035
+K3B = -8.2369696    W0 = 1.041146E-8        K3 = 24.0984767
+DVT0W = 0           DVT1W = 0           NLX = 1E-9
+DVT0 = 2.7123969    DVT1 = 0.4232931        DVT2W = 0
+U0 = 451.2322004    UA = 3.091785E-13     DVT2 = -0.1403765
+UC = 1.22401E-11    VSAT = 1.715884E5      UB = 1.702517E-18
+AGS = 0.130484      B0 = 2.446405E-6        A0 = 0.6580918
+KETA = -3.043349E-3 A1 = 8.18159E-7         B1 = 5E-6
+RDSW = 1.367055E3   PRWG = 0.0328586       A2 = 0.3363058
+WR = 1              WINT = 2.443677E-7     PRWB = 0.0104806
+XL = 1E-7           XW = 0                 LINT = 6.999776E-8
+DWB = 3.676235E-8   VOFF = -1.493503E-4    DWG = -1.256454E-8
+CIT = 0             CDSC = 2.4E-4          NFACTOR = 1.0354201
+CDSCB = 0          ETA0 = 2.342963E-3     CDSCD = 0
+DSUB = 0.0764123   PCLM = 2.5941582       ETAB = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505   PDIBLC1 = 0.8187825
+PSCBE1 = 6.611774E8 PSCBE2 = 3.238266E-4   DROUT = 0.9919348
+PRT = 0            UTE = -1.5             PVAG = 0
+KT1L = 0           KT2 = 0.022            KT1 = -0.11
+UB1 = -7.61E-18    UC1 = -5.6E-11        UA1 = 4.31E-9
+WL = 0             WLN = 1                AT = 3.3E4
+WWN = 1            WWL = 0                WW = 0
+LLN = 1            LW = 0                 LL = 0
+LWL = 0            CAPMOD = 2             LWN = 1
+CGDO = 2.32E-10    CGSO = 2.32E-10       XPART = 0.5
+CJ = 4.282017E-4   PB = 0.9317787        CGBO = 1E-9
+CJSW = 3.034055E-10 PBSW = 0.8             MJ = 0.4495867
+CJSWG = 1.64E-10  PBSWG = 0.8           MJSW = 0.1713852
+CF = 0             PVTH0 = 0.0520855     MJSWG = 0.1713852
+PK2 = -0.0289036  WKETA = -0.0237483    PRDSW = 112.8875816
*                  )    LKETA = 1.728324E-3
```

# Model Errors with Different W/L Values



Binning models can improve model accuracy

# BSIM Binning Model

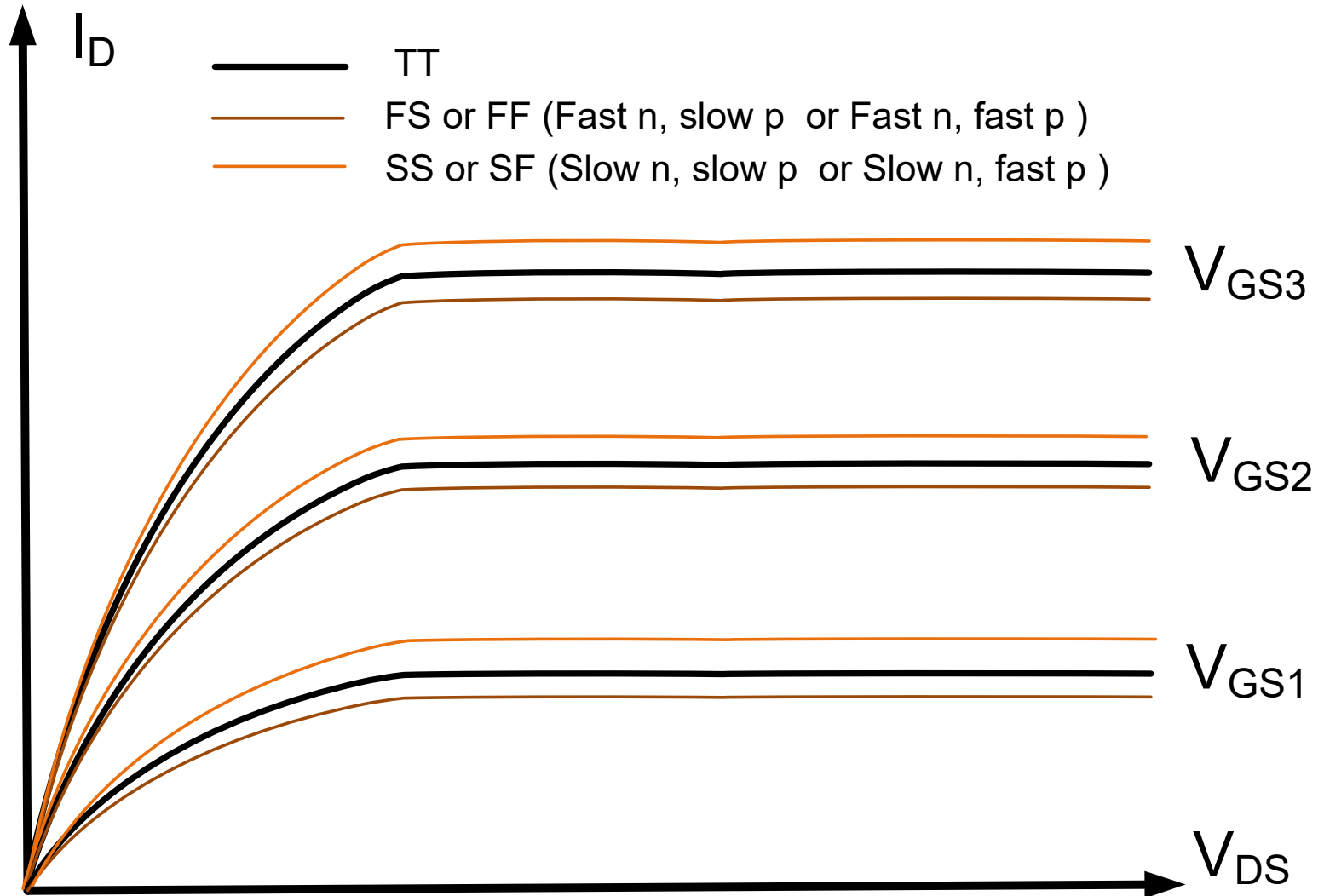
- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          LEVEL = 49
+XJ = 1.5E-7          NCH = 1.7E17        TOX = 1.42E-8
+K1 = 0.8976376      K2 = -0.09255       VTH0 = 0.629035
+K3B = -8.2369696    W0 = 1.041146E-8        K3 = 24.0984767
+DVT0W = 0           DVT1W = 0          NLX = 1E-9
+DVT0 = 2.7123969    DVT1 = 0.4232931        DVT2W = 0
+U0 = 451.2322004    UA = 3.091785E-13     DVT2 = -0.1403765
+UC = 1.22401E-11    VSAT = 1.715884E5      UB = 1.702517E-18
+AGS = 0.130484      B0 = 2.446405E-6       A0 = 0.6580918
+KETA = -3.043349E-3 A1 = 8.18159E-7        B1 = 5E-6
+RDSW = 1.367055E3   PRWG = 0.0328586      A2 = 0.3363058
+WR = 1              WINT = 2.443677E-7    PRWB = 0.0104806
+XL = 1E-7           XW = 0                 LINT = 6.999776E-8
+DWB = 3.676235E-8   VOFF = -1.493503E-4   DWG = -1.256454E-8
+CIT = 0             CDSC = 2.4E-4          NFACTOR = 1.0354201
+CDSCB = 0           ETA0 = 2.342963E-3    CDSCD = 0
+DSUB = 0.0764123    PCLM = 2.5941582      ETAB = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1 = 6.611774E8 PSCBE2 = 3.238266E-4  DROUT = 0.9919348
                    PVAG = 0
+PRT = 0             UTE = -1.5            KT1 = -0.11
+KT1L = 0            KT2 = 0.022           UA1 = 4.31E-9
+UB1 = -7.61E-18     UC1 = -5.6E-11       AT = 3.3E4
+WL = 0              WLN = 1              WW = 0
+WWN = 1             WWL = 0              LL = 0
+LLN = 1             LW = 0               LWN = 1
+LWL = 0             CAPMOD = 2           XPART = 0.5
+CGDO = 2.32E-10     CGSO = 2.32E-10      CGBO = 1E-9
+CJ = 4.282017E-4    PB = 0.9317787       MJ = 0.4495867
+CJSW = 3.034055E-10 PBSW = 0.8            MJSW = 0.1713852
+CJSWG = 1.64E-10    PBSWG = 0.8          MJSWG = 0.1713852
+CF = 0              PVTH0 = 0.0520855    PRDSW = 112.8875816
+PK2 = -0.0289036   WKETA = -0.0237483   LKETA = 1.728324E-3
*)
*
```

With 32 bins, this model has 3040 model parameters !

# Model Changes with Process Variations

(n-ch characteristics shown)



Corner models can improve model accuracy

# BSIM Corner Models with Binning

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- bin on device sizes

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          TOX = 1.42E-8
+XJ = 1.5E-7           NCH = 1.7E17       VTH0 = 0.629035
+K1 = 0.8976376       K2 = -0.09255      K3 = 24.0984767
+K3B = -8.2369696     W0 = 1.041146E-8     NLX = 1E-9
+DVT0W = 0            DVT1W = 0            DVT2W = 0
+DVT0 = 2.7123969     DVT1 = 0.4232931    DVT2 = -0.1403765
+U0 = 451.2322004     UA = 3.091785E-13   UB = 1.702517E-18
+UC = 1.22401E-11     VSAT = 1.715884E5   A0 = 0.6580918
+AGS = 0.130484       B0 = 2.446405E-6    B1 = 5E-6
+KETA = -3.043349E-3  A1 = 8.18159E-7     A2 = 0.3363058
+RDSW = 1.367055E3    PRWG = 0.0328586    PRWB = 0.0104806
+WR = 1               WINT = 2.443677E-7  LINT = 6.999776E-8
+XL = 1E-7            XW = 0              DWG = -1.256454E-8
+DWB = 3.676235E-8    VOFF = -1.493503E-4 NFACTOR = 1.0354201
+CIT = 0              CDSC = 2.4E-4        CDSCD = 0
+CDSCB = 0            ETA0 = 2.342963E-3  ETAB = -1.5324E-4
+DSUB = 0.0764123     PCIM = 2.5941582    PDIBLC1 = 0.8187825
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505 DROUT = 0.9919348
+PSCBE1 = 6.611774E8  PSCBE2 = 3.238266E-4 PVAG = 0
+DPR.TA = 0.01        RSH = 83.5          MORMOD = 1
+PRT = 0              UTE = -1.5          KT1 = -0.11
+KT1L = 0             KT2 = 0.022         UA1 = 4.31E-9
+UB1 = -7.61E-18      UC1 = -5.6E-11      AT = 3.3E4
+WL = 0               WLN = 1             WW = 0
+WWN = 1              WWL = 0             LL = 0
+LLN = 1              LW = 0              LWN = 1
+LWL = 0              CAPMOD = 2          XPART = 0.5
+CGDO = 2.32E-10      CGSO = 2.32E-10     CGBO = 1E-9
+CJ = 4.282017E-4     PB = 0.9317787      MJ = 0.4495867
+CJSW = 3.034055E-10  PBSW = 0.8          MJSW = 0.1713852
+CJSWG = 1.64E-10     PBSWG = 0.8         MJSWG = 0.1713852
+CF = 0               PVTH0 = 0.0520855  PRDSW = 112.8875816
+PK2 = -0.0289036     WKETA = -0.0237483  LKETA = 1.728324E-3 )
*
```

With 32 size bins and 4 corners, this model has 15,200 model parameters !



# How many models of the MOSFET do we have?

Switch-level model (2)

Square-law model

Square-law model (with  $\lambda$  and bulk additions)

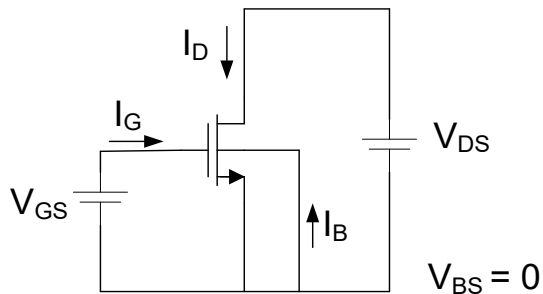
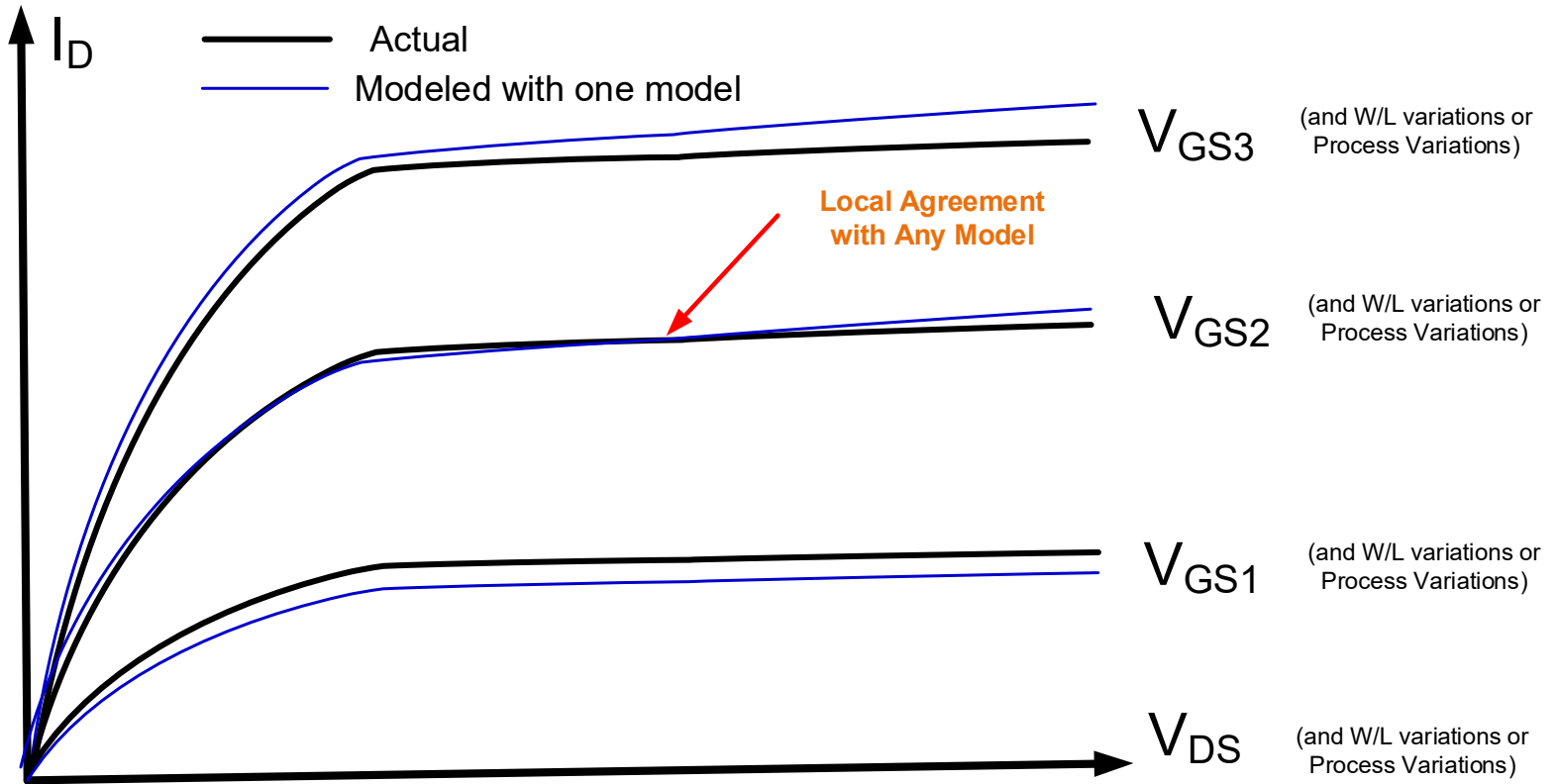
$\alpha$ -law model (with  $\lambda$  and bulk additions)

BSIM model

BSIM model (with binning extensions)

BSIM model (with binning extensions and process corners)

# The Modeling Challenge



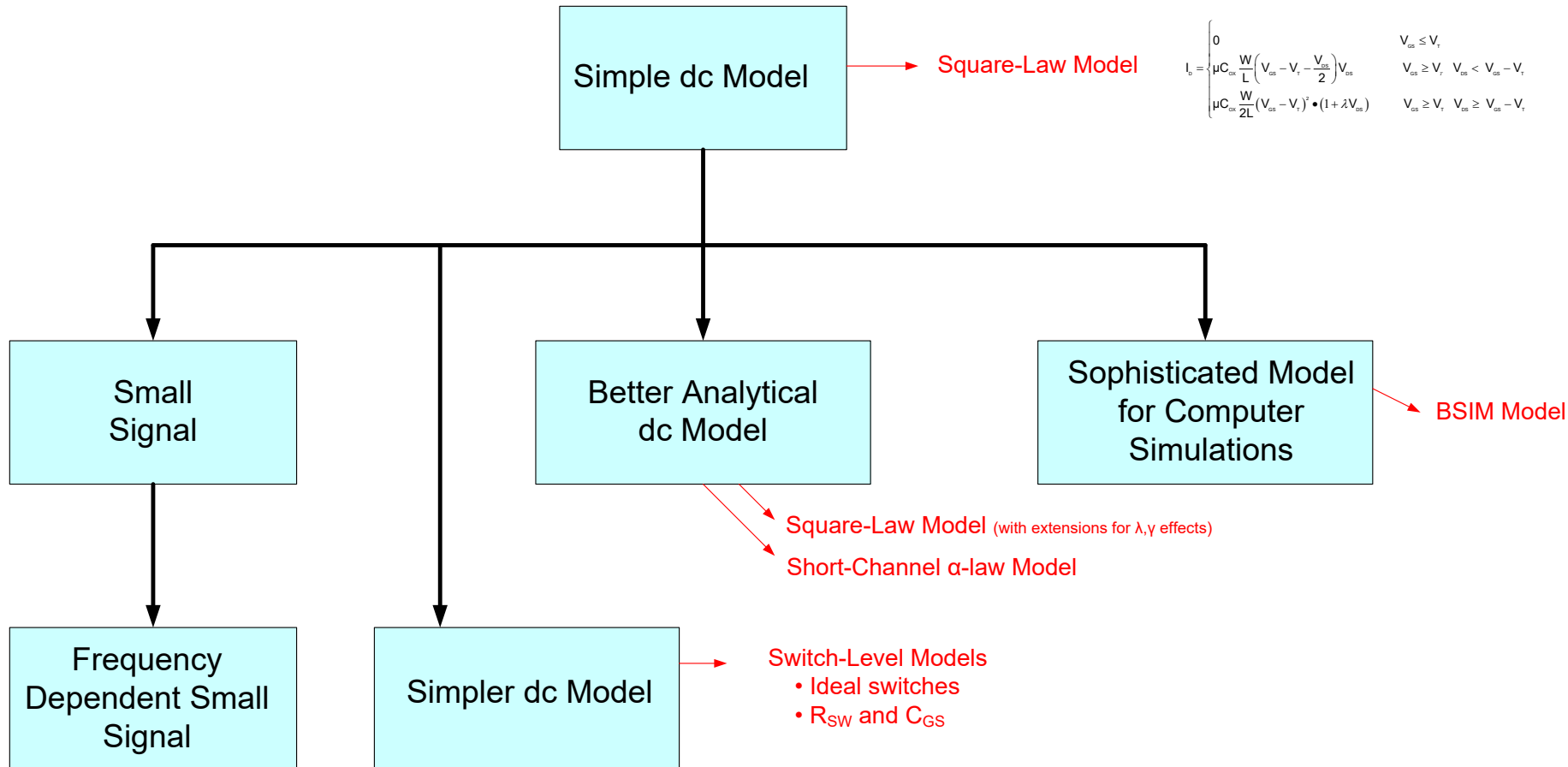
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

Difficult to obtain analytical functions that accurately fit actual devices over bias, size, and process variations

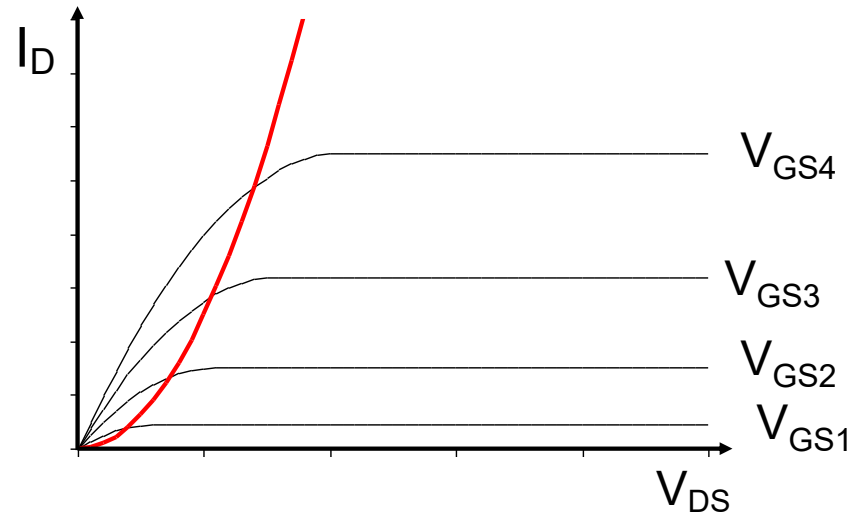
# Model Status



In the next few slides, the models we have developed will be listed and reviewed

- Square-law Model
- Switch-level Models
- Extended Square-law model
- Short-channel model
- BSIM Model
- BSIM Binning Model
- Corner Models

# Square-Law Model

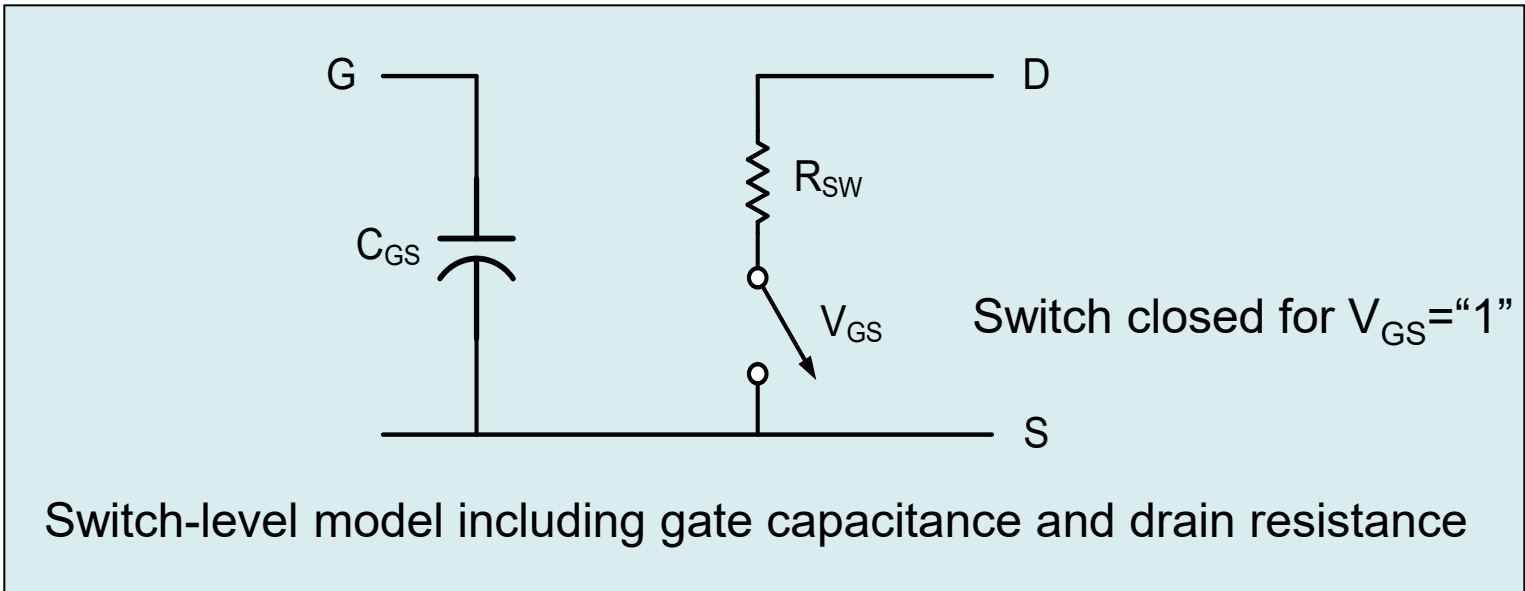
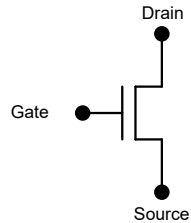


$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

Model Parameters :  $\{\mu, C_{OX}, V_{TH0}\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom  $W/L$

# Switch-Level Models



$C_{GS}$  and  $R_{SW}$  dependent upon device sizes and process

For minimum-sized devices in a 0.5u process

$$\mathbf{C_{GS} \cong 1.5fF} \quad \mathbf{R_{sw} \cong \left. \begin{array}{l} 2K\Omega \text{ n-channel} \\ 6K\Omega \text{ p-channel} \end{array} \right\}}$$

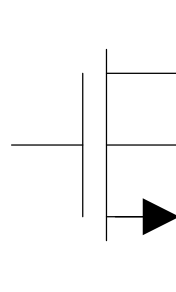
Considerable emphasis will be placed upon device sizing to manage  $C_{GS}$  and  $R_{SW}$

Model Parameters :  $\{C_{GS}, R_{SW}\}$

# Extended Square-Law Model

$$I_G = 0$$

$$I_B = 0$$



$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \mu C_{OX} \frac{W}{L} \left( V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < V_{GS} - V_{TH} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_{TH})^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_{TH} \quad V_{DS} \geq V_{GS} - V_{TH} \end{cases}$$

$$V_{TH} = V_{TH0} + \gamma \left( \sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Model Parameters :  $\{\mu, C_{OX}, V_{TH0}, \phi, \gamma, \lambda\}$

Design Parameters :  $\{W, L\}$  but only one degree of freedom  $W/L$

# Short-Channel Model

$$I_D = \begin{cases} 0 & V_{GS} \leq V_{TH} \\ \frac{\theta_2}{\theta_1} \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_{TH} \quad V_{DS} < \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH})^{\alpha} & V_{GS} \geq V_{TH} \quad V_{DS} \geq \theta_1 (V_{GS} - V_{TH})^{\frac{\alpha}{2}} \end{cases}$$

$\alpha$  is the velocity saturation index,  $2 \geq \alpha \geq 1$

Channel length modulation ( $\lambda$ ) and bulk effects can be added to the velocity Saturation as well



# BSIM model

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          TOX      = 1.42E-8
+XJ      = 1.5E-7       NCH     = 1.7E17       VTH0     = 0.629035
+K1      = 0.8976376    K2     = -0.09255      K3       = 24.0984767
+K3B     = -8.2369696   W0     = 1.041146E-8  NLX      = 1E-9
+DVT0W   = 0           DVT1W  = 0           DVT2W    = 0
+DVT0    = 2.7123969   DVT1   = 0.4232931   DVT2     = -0.1403765
+U0      = 451.2322004 UA     = 3.091785E-13  UB       = 1.702517E-18
+UC      = 1.22401E-11 VSAT   = 1.715884E5   A0       = 0.6580918
+AGS     = 0.130484    B0     = 2.446405E-6  B1       = 5E-6
+KETA    = -3.043349E-3 A1     = 8.18159E-7   A2       = 0.3363058
+RDSW    = 1.367055E3  PRWG   = 0.0328586   PRWB     = 0.0104806
+WR      = 1           WINT   = 2.443677E-7  LINT     = 6.999776E-8
+XL      = 1E-7       XW     = 0           DWG      = -1.256454E-8
+DWB     = 3.676235E-8 VOFF   = -1.493503E-4 NFACTOR  = 1.0354201
+CIT     = 0           CDSC   = 2.4E-4       CDSCD    = 0
+CDSCB   = 0           ETA0   = 2.342963E-3   ETAB     = -1.5324E-4
+DSUB    = 0.0764123  PCLM   = 2.5941582   PDIBLC1  = 0.8187825
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505   DROUT    = 0.9919348
+PSCBE1  = 6.611774E8 PSCBE2 = 3.238266E-4  PVAG     = 0

+PRT     = 0           UTE    = -1.5         KT1      = -0.11
+KT1L    = 0           KT2    = 0.022        UA1      = 4.31E-9
+UB1     = -7.61E-18  UC1    = -5.6E-11     AT       = 3.3E4
+WL      = 0           WLN    = 1           WW       = 0
+WWN     = 1           WWL    = 0           LL       = 0
+LLN     = 1           LW     = 0           LWN     = 1
+LWL     = 0           CAPMOD = 2           XPART    = 0.5
+CGDO    = 2.32E-10   CGSO   = 2.32E-10    CGBO     = 1E-9
+CJ      = 4.282017E-4 PB      = 0.9317787   MJ       = 0.4495867
+CJSW    = 3.034055E-10 PBSW   = 0.8           MJSW    = 0.1713852
+CJSWG   = 1.64E-10  PBSWG  = 0.8           MJSWG   = 0.1713852
+CF      = 0           PVTH0  = 0.0520855     PRDSW   = 112.8875816
+PK2     = -0.0289036 WKETA  = -0.0237483     LKETA   = 1.728324E-3 )
*
```

Note this model has 95 model parameters !

# BSIM Binning Model

- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          LEVEL = 49
+XJ = 1.5E-7          NCH = 1.7E17        TOX = 1.42E-8
+K1 = 0.8976376      K2 = -0.09255       VTH0 = 0.629035
+K3B = -8.2369696    W0 = 1.041146E-8      K3 = 24.0984767
+DVT0W = 0           DVT1W = 0          NLX = 1E-9
+DVT0 = 2.7123969    DVT1 = 0.4232931      DVT2W = 0
+U0 = 451.2322004    UA = 3.091785E-13    DVT2 = -0.1403765
+UC = 1.22401E-11    VSAT = 1.715884E5     UB = 1.702517E-18
+AGS = 0.130484      B0 = 2.446405E-6      A0 = 0.6580918
+KETA = -3.043349E-3 A1 = 8.18159E-7       B1 = 5E-6
+RDSW = 1.367055E3   PRWG = 0.0328586     A2 = 0.3363058
+WR = 1              WINT = 2.443677E-7   PRWB = 0.0104806
+XL = 1E-7           XW = 0                LINT = 6.999776E-8
+DWB = 3.676235E-8   VOFF = -1.493503E-4  DWG = -1.256454E-8
+CIT = 0             CDSC = 2.4E-4         NFACTOR = 1.0354201
+CDSCB = 0           ETA0 = 2.342963E-3   CDSCD = 0
+DSUB = 0.0764123    PCLM = 2.5941582     ETAB = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1 = 6.611774E8 PSCBE2 = 3.238266E-4  DROUT = 0.9919348
                    PVAG = 0
+PRT = 0             UTE = -1.5           KT1 = -0.11
+KT1L = 0            KT2 = 0.022          UA1 = 4.31E-9
+UB1 = -7.61E-18     UC1 = -5.6E-11       AT = 3.3E4
+WL = 0              WLN = 1              WW = 0
+WWN = 1             WWL = 0              LL = 0
+LLN = 1             LW = 0               LWN = 1
+LWL = 0             CAPMOD = 2           XPART = 0.5
+CGDO = 2.32E-10     CGSO = 2.32E-10     CGBO = 1E-9
+CJ = 4.282017E-4    PB = 0.9317787      MJ = 0.4495867
+CJSW = 3.034055E-10 PBSW = 0.8           MJSW = 0.1713852
+CJSWG = 1.64E-10    PBSWG = 0.8         MJSWG = 0.1713852
+CF = 0              PVTH0 = 0.0520855   PRDSW = 112.8875816
+PK2 = -0.0289036   WKETA = -0.0237483  LKETA = 1.728324E-3 )
*
```

With 32 bins, this model has 3040 model parameters !

# BSIM Corner Models

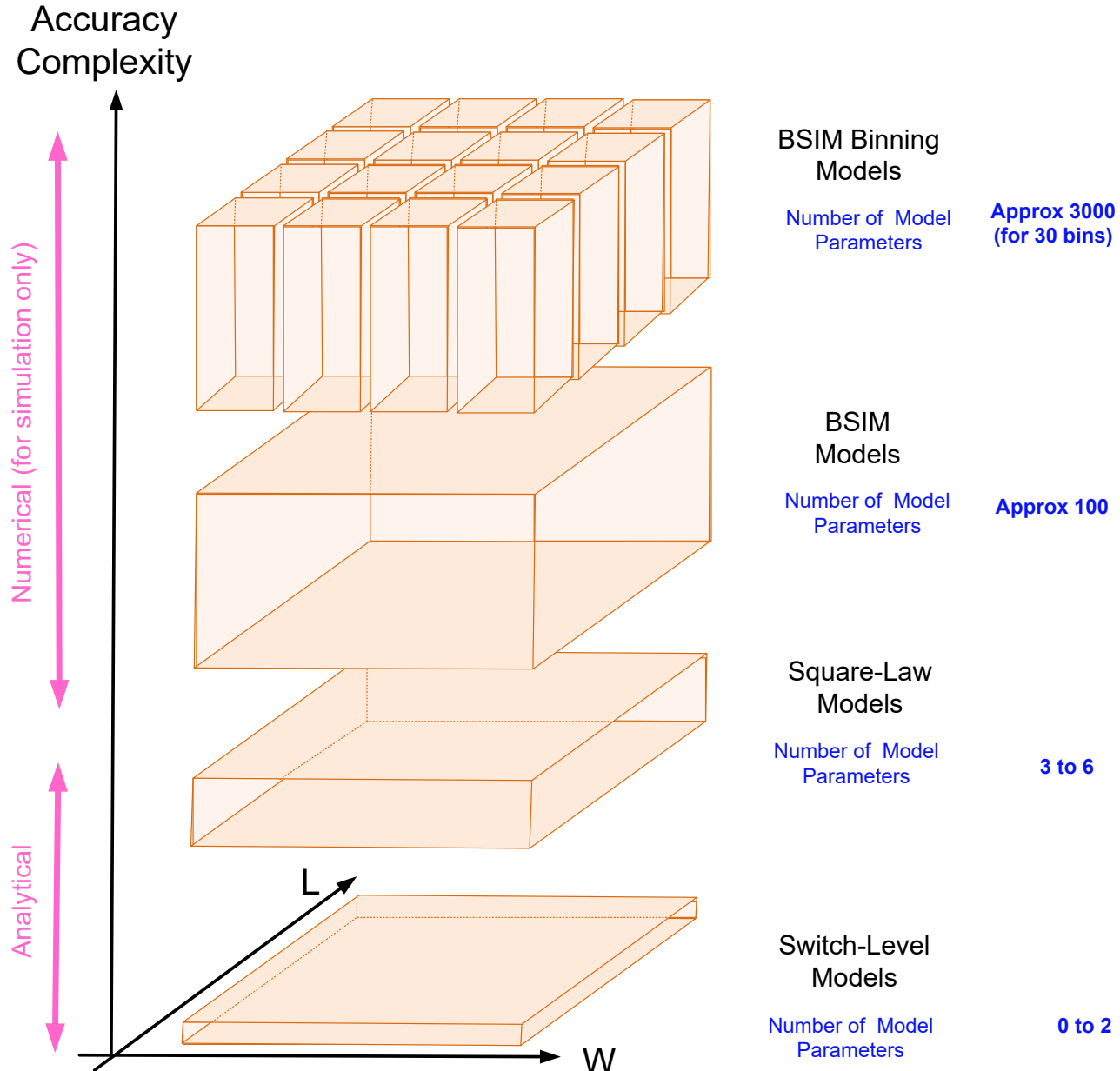
- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS
- five different BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          TOX      = 1.42E-8
+XJ      = 1.5E-7      NCH    = 1.7E17      VTH0     = 0.629035
+K1      = 0.8976376   K2     = -0.09255    K3       = 24.0984767
+K3B     = -8.2369696  W0     = 1.041146E-8 NLX      = 1E-9
+DVT0W   = 0          DVT1W  = 0          DVT2W    = 0
+DVT0    = 2.7123969  DVT1   = 0.4232931  DVT2     = -0.1403765
+U0      = 451.2322004 UA     = 3.091785E-13  UB       = 1.702517E-18
+UC      = 1.22401E-11 VSAT   = 1.715884E5   A0       = 0.6580918
+AGS     = 0.130484   B0     = 2.446405E-6  B1       = 5E-6
+KETA    = -3.043349E-3 A1     = 8.18159E-7   A2       = 0.3363058
+RDSW    = 1.367055E3 PRWG   = 0.0328586   PRWB     = 0.0104806
+WR      = 1          WINT   = 2.443677E-7 LINT     = 6.999776E-8
+XL      = 1E-7       XW     = 0          DWG      = -1.256454E-8
+DWB     = 3.676235E-8 VOFF   = -1.493503E-4 NFACTOR  = 1.0354201
+CIT     = 0          CDSC   = 2.4E-4      CDSCD    = 0
+CDSCB   = 0          ETA0   = 2.342963E-3  ETAB     = -1.5324E-4
+DSUB    = 0.0764123 PCLM   = 2.5941582   PDIBLC1  = 0.8187825
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505    DROUT    = 0.9919348
+PSCBE1  = 6.611774E8 PSCBE2 = 3.238266E-4  PVAG     = 0
+DRIFTA  = 0.01      RSH    = 83.5       MORMOD   = 1
+PRT     = 0          UTE    = -1.5      KT1      = -0.11
+KT1L    = 0          KT2    = 0.022     UA1      = 4.31E-9
+UB1     = -7.61E-18 UC1     = -5.6E-11  AT       = 3.3E4
+WL      = 0          WLN    = 1         WW       = 0
+WWN     = 1          WWL    = 0         LL       = 0
+LLN     = 1          LW     = 0         LWN     = 1
+LWL     = 0          CAPMOD = 2         XPART   = 0.5
+CGDO    = 2.32E-10  CGSO   = 2.32E-10  CGBO     = 1E-9
+CJ      = 4.282017E-4 PB      = 0.9317787  MJ       = 0.4495867
+CJSW    = 3.034055E-10 PBSW   = 0.8        MJSW    = 0.1713852
+CJSWG   = 1.64E-10  PBSWG  = 0.8        MJSWG   = 0.1713852
+CF      = 0          PVTH0  = 0.0520855  PRDSW   = 112.8875816
+PK2     = -0.0289036 WKETA  = -0.0237483  LKETA   = 1.728324E-3 )
*
```

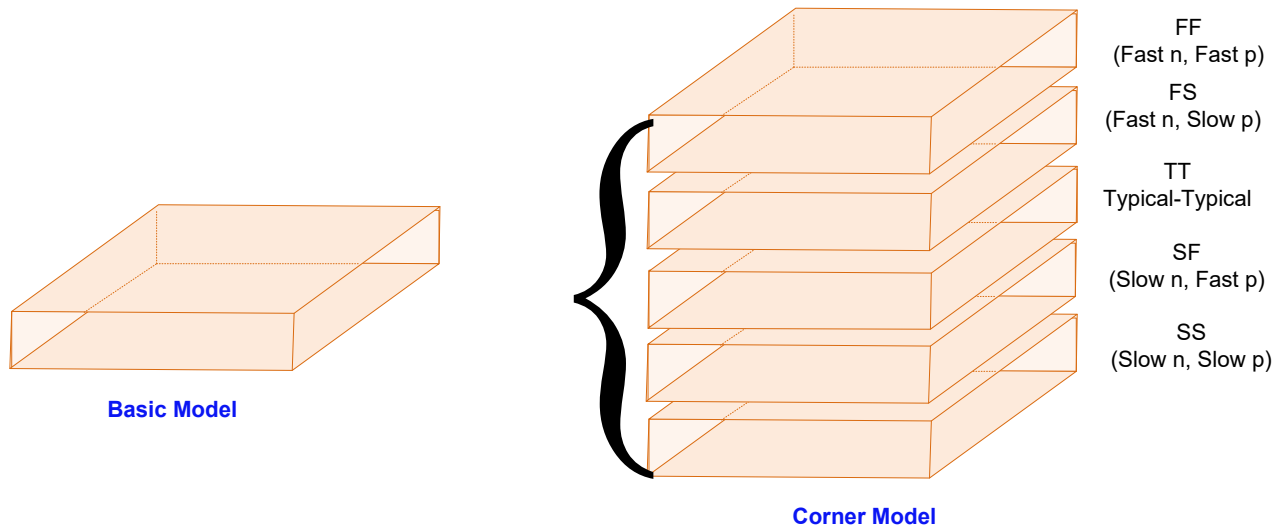
TT: typical-typical  
 FF: fast n, fast p  
 FS: fast n, slow p  
 SF: slow n, fast p  
 SS: slow n, slow p

With 4 corners, this model has 475 model parameters !

# Hierarchical Model Comparisons



# Corner Models



Applicable at any level in model hierarchy (same model, different parameters)

Often 4 corners (FF, FS, SF, SS) used but sometimes many more

Designers must provide enough robustness so good yield at all corners



Stay Safe and Stay Healthy !

End of Lecture 17